



# i.MX 6 Series Thermal Management Guidelines

Document Number: AN4579  
Rev. 0, 11/2012



# i.MX 6 Series - Thermal Management Guidelines

## ➤ Overview

- General overview of the thermal issues when using high performance applications
- The relationship between power consumption , heat and activity profile (duty-cycle) for a system

## ➤ Thermal Management Concepts

- General thermal related terms, thermal resistance (and conductivity)
- Thermal management solutions: heat spreaders, thermal gap fillers

## ➤ Thermal Attributes

- i.MX 6Dual/6Quad thermal package specifications (defined by JEDEC).
- Building thermal models (using package details, board details)
- Thermal solutions and tradeoffs

## ➤ Thermal Simulations

- How to simulate heat at the system level: board, components, enclosure and tools
- Assumptions of models used in simulations and the summary of thermal simulation results

## ➤ Software Thermal Management Techniques

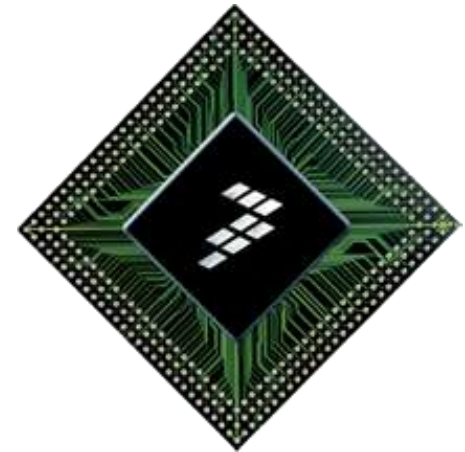
- Software thermal management techniques
- Software implemented features to manage power and provide thermal regulation

## ➤ Recommendations /Conclusion

- Final recommendations based on simulation results

## ➤ Appendix /References

- Additional References and Resources
- Heat spreading examples based on other vendors





- **Overview**
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# Overview : Thermal Management

The i.MX 6 series of multimedia-focused products offer high performance processing optimized for the lowest power consumption. For such high performance devices, the power dissipation of the device requires that customers consider the thermal performance of the device and design their system accordingly.

Thermal management becomes critical when the power dissipation level increases in certain high performance use cases. Under these use cases integrated thermal management from package to the system level is needed to ensure the performance and reliability of the i.MX 6Dual/6Quad SoC and the system:

- **Operating Environment** : Thermal management becomes a challenge especially when operating in a high ambient temperature environment. One way to constrain the environment ambient operating temperature for the device is to ensure it must be at or lower than a given temperature.
- **Expected Power Consumption**: This depends on the modes of operation, and the use-cases that the system will be running. Dynamic power is a nonlinear function of capacitance, frequency, and volts squared ( $P_{\text{dynamic}} = CfV^2$ ). The nonlinear nature of this relationship illustrates that as the switching frequency gets higher, the amount of power and heat grows exponentially. Operating at the highest frequency to achieve the highest performance implies paying a penalty in terms of power consumption (battery life), and dissipated power in the form of heat. Different thermal solutions are required depending on the system power and utilization
- **Device Usage & Operational Duty Cycle** : The operational duration at various environment conditions needs to be considered. Understanding the target operation duty cycle is important when considering the end thermal solution for the system



# Overview : Thermal Management

## Consume Less Power - Generate Less heat

Heat in an embedded system is a by-product of power and the best way to generate less heat is to consume less power. Once heat is generated, the job then becomes to transfer it effectively by providing an efficient path from the device to the environment via thermal pads, epoxy or any method that makes use of conduction, convection, or facilitates radiation.

The general strategy for thermal management focuses on:

- **Increasing the heat-dissipation** capability of the thermal solutions
- **Expanding the thermal envelopes** of systems
- Minimizing impact of local hot spots **by improving heat spreading**
- Developing **thermal solutions** that meet **cost constraints**
- Solutions that **fit within form factor** considerations of the product chassis



## Thermal Management Strategies

There are basically two types of thermal management strategies:

- **Active** thermal management techniques available for embedded systems provide lower thermal resistances and better heat dissipation, however are expensive and have large form factors
- **Passive** thermal management techniques by enhancing conduction and natural convection provide more cost effective solutions, up to certain power levels without introducing any reliability concerns and are discussed primarily in this report for the i.MX 6Dual/6Quad SoC



# Overview : Thermal Management System Design

## Thermal Design Strategy

A holistic thermal design strategy needs to consider all aspects of the thermal hierarchy. Historically, the processor was the most energy hungry component of a typical embedded computing system. However, processors such as the i.MX6 family have become more energy efficient and more effective at managing their own power consumption (thanks to sophisticated power/clock management architectures and techniques).

In contrast, memory energy consumption has been growing, as multi-core CPUs with multiple hardware accelerators are requiring increasing DDR memory bandwidth and capacity. The main system memory (DDR) can consume significant system energy in active modes. Hence the main system memory power, equally challenges both power management system and thermal design.

## Thermal Contributors

Customers also need to consider the impact of other components on the system board due to their heat generating capacity. Typical high power devices in a system include but are not limited to the following:

- Power Management IC's or External LDO's
- RF components such as PA, transmitters & Modems
- LCD, LED and OLED displays
- High Speed memories and Transceivers

Although many of the techniques discussed in this document apply to all heat generating components, we primarily focus on the i.MX 6 series and i.MX 6Dual/6Quad SoC in particular. Memory power savings are briefly discussed in the Software Thermal Management Techniques section of this document.



# Overview : Thermal Dissipation

## Thermal Design Power

The Thermal Design Power (TDP), also referred to the thermal design point, is of primary interest to the thermal solution designer and it represents the maximum sustained power dissipated by the i.MX 6Dual/6Quad processor, across a set of realistic applications. Designing for TDP is important to ensure reliable long-term performance.

## Thermal Time Constant

The steady state is predicted by the thermal resistances, but the time constant to get there is significant. This time constant sets the length of time to average the consumption of the chip over for bursty operations and will scale up and down with the board and packaging size/mass. It is possible for there to be brief bursts of activity where the power dissipated is larger than the target TDP, but no action is required as long as the bursts are within the thermal time constant and do not violate the i.MX 6Dual/6Quad thermal specifications.

Some of the typical usage profiles are natively bursty - internet browsing (burst per user activity), video/audio playback (periodical bursts associated with frame processing). For instance, when we perform temperature sensor testing, we need to wait for the chip and board to stabilize thermally once at the correct temperature. This is discussed further in the Software Thermal Management Techniques section of this document.



# Overview : Thermal Dissipation Activity Profile

The activity profile of the application can have a significant impact on the thermal management techniques that need to be employed, and on the thermal design power. The main types of activities can be classified as follows:

- **Short Bursts** below thermal time constant
  - Short bursts of intensive processing followed by long intervals of the IC/System being idle can automatically regulate the heat without much external intervention.
- **Long Bursts** above thermal time constant
  - Long bursts of intensive processing followed by long intervals of the IC/System being idle may require some external intervention such as software thermal management.
- **Continuous Operation** at an average power
  - However continuous high performance usage without any idling can cause the system temperature to rise, hence making it necessary to have other forms of thermal management.

The more intensive the use case with all major power contributors active such as the ARM Cores and Graphics Processing Unit (GPU) the higher the potential thermal energy that needs to be effectively dissipated.

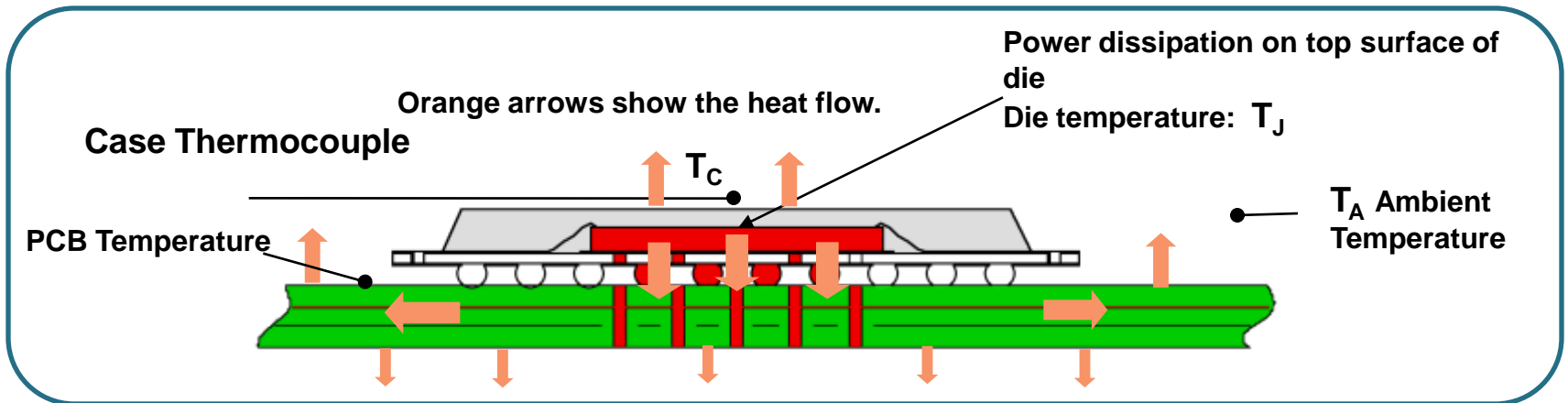




# Overview : Thermal Dissipation

## Primary Heat Path

Thermal Simulations and testing have shown that the dominant heat transfer inside small form factor devices is via conduction due to the confined space inside the enclosure, where the natural convection effect is even negligible. Most of the heat generated by a high power component is dissipated through the system board, when no thermal solution is implemented on the top of the package, which indicates that the primary heat path is from junction to the board.

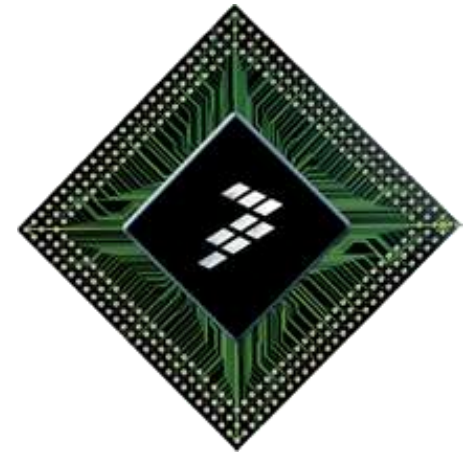


Power dissipated in the die is conducted to the top surface of the package and to the board and then dissipated to the environment.

- $T_j$  "Junction" or die temperature
- $T_A$  Ambient or air temperature near the device
- $T_B$  Board temperature at the edge of the device
- $T_c$  Case temperature



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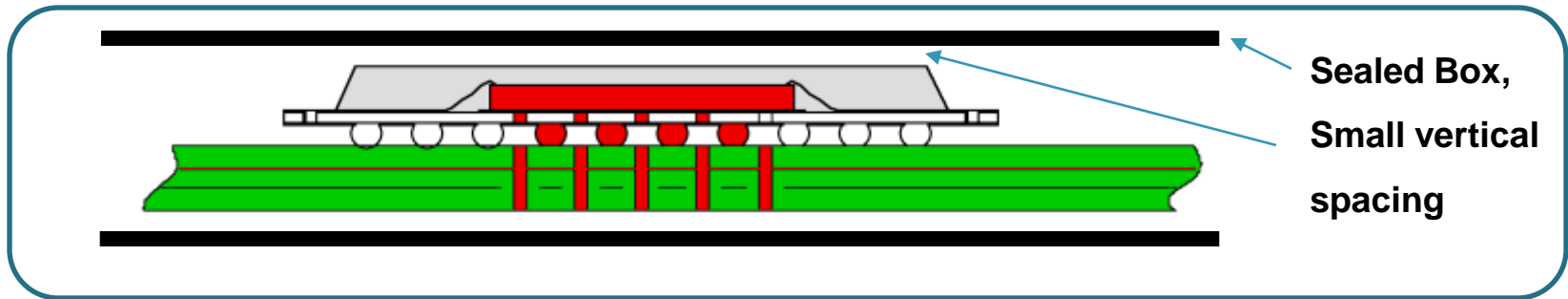


# Thermal Management Techniques

## Passive Thermal Management

This section investigates various passive thermal management strategies and primarily focuses on handheld devices with small form factors. Spreading heat and cooling components in handheld devices poses unique problems.

Because of the high density of components and small form factor, very little room is available for a thermal solution. Given the limited airflow and the presence of significant amounts of lower thermal conductivity material heat dissipation becomes a challenge. Most heat transfer is by conduction and radiation.



Passive thermal management techniques that are typically used are listed below:

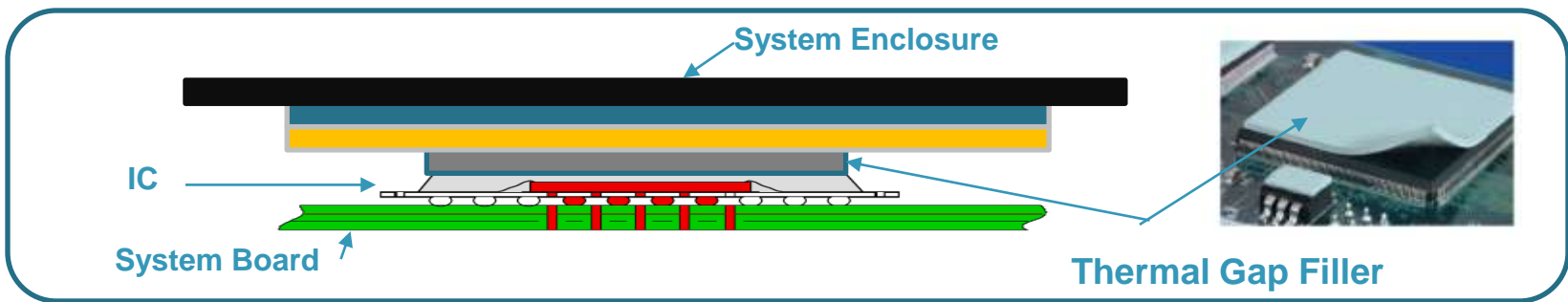
- Thermal Gap Fillers/Thermal Interface Materials
- Heat Spreaders
  - Copper
  - Graphite
- Heat Shields



# Thermal Management Techniques

## Thermal Gap Filler

A Gap filler is typically placed between the top/bottom of the high power component and case, removing air gap around the package, which is a thermal barrier due to very minimal air circulation. The thermo-elastic gap filler material is often found in the handheld device for thermal management purpose as well as for better shock resistance.



- The use of a **gap filler with a higher thermal conductivity** will result in better thermal dissipation capability. It helps in reducing the junction temperature ( $T_j$ ), however, if used in isolation the direct heat path from the package to the system enclosure results in the skin temperature rise, generating hot spots
- Complete **elimination of the air gap inside** the system using a gap filler material has significant thermal benefits however the thermal benefit from the use of gap filler is significantly limited by the heat spreading capability of the system enclosure
- **Proper attachment** of the gap filler is important as well as using the correct thermal contact adhesives. Improper application can severely reduce the thermal conductivity of the filler. Data will be presented in subsequent thermal simulation section for comparisons



# Thermal Management Techniques

## Heat Spreaders

### The Need for Heat Spreaders

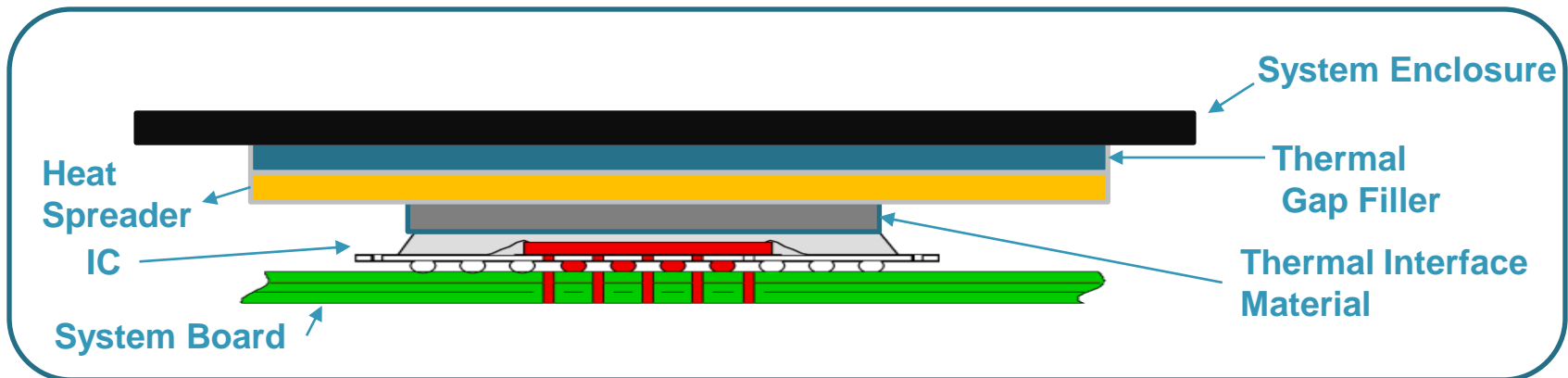
- Providing the conduction heat path between the package and the system enclosure, alone, may not be sufficient enough for thermal management of high power component for extended operations
- The gap filler material can serve as temporary thermal storage, delaying the time to reach steady state, however, is not sufficient to dissipate the thermal energy
- For extended operation or for high power consuming use cases, enhancing the heat spreading capability of the device enclosure becomes critical
- Heat spreaders are used to spread the heat while transporting it from the die to the PCB, product chassis or a heat sink (if the product design form factor permits), which in turn dissipates heat to the local environment
- To increase cooling capability, the strategy is to even out the temperature profiles due to non uniform power distributions, as close to the source as possible, by spreading out the heat. Heat spreaders serve three primary purposes:
  - Touch Temperature Reduction
  - High power/hot component temperature reduction/cooling
  - Shielding heat
- The next part of this document discusses the advantages of heat spreaders along with some of the design considerations for heat spreader material selection and placement in the final product



# Thermal Management Techniques

## Heat Spreaders

- A thermally conductive heat spreader can be placed on the high power components and this heat spreader can enable spreading and evening out of the hot spots and could be designed to make direct contact with the system enclosure as shown below:



- This design concept significantly increased the power dissipation capability, by reducing overall system thermal resistance.
- The type of heat spreader to be used is dependent on the customers' application available enclosure space and budget considerations



# Thermal Management Techniques

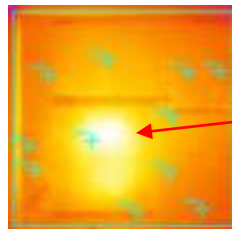
## Copper Heat Spreaders

### Copper Advantages

- Copper has been used extensively in many thermal applications including heat spreaders
- The excellent thermal conductivity of copper(400W/mK) in all directions (x,y & z) makes it an effective heat spreader
- Simulations with the Copper heat spreader always showed better heat dissipation capability when comparing a model without the heat spreader, again due to better heat dissipation capability
- Simulations and testing performed clearly show the benefits of using a heat spreader. Please refer to the Thermal Simulations section of this document for further information

### Copper Limitations

- Although copper does have good thermal conductivity the increasing cost of copper has made it more inhibitive for mass deployment. Hence the area of the copper could be limited to the area on the enclosure to reduce cost or by using cheaper copper tape
- The thermal conductivity of copper(400W/K) in all directions can be problematic since a hot spot could just translate vertically to a different location, possibly closer to the enclosure hence creating a hot spot on the case. Copper hence is not best suited for touch temperature reduction applications.



Hot Spot on a high power component can easily appear as a similar hot spot on a copper spreader if not sized correctly



# Thermal Management Techniques

## Graphite Heat Spreaders

- Graphite matches the thermal performance of copper in two directions(x,y), at a lower weight and cost.
- Due to its relatively low cost, the area that the graphite heat spreader covers ,could be potentially large, covering all heat generating components
- Flexible graphite heat spreaders give product designers the tools to overcome the complex challenges associated with thermal management
- Some of the key product applications are listed below
  - Cooling of sensitive components
  - Elimination of fans & active cooling
  - Touch temperature reduction
  - Thermal shielding of Li-Ion batteries
  - Cooling of LED and power components
  - Mitigation of AMOLED and LCD display hot spots
    - Improves brightness uniformity
    - Decreases image sticking and burn-in
    - Minimizes warping of back light unit and films
    - Reduces chassis distortion
    - Reduces the severity of stress-induced birefringence
- Applications of Graphite heat spreaders in actual products are shown in Appendix E



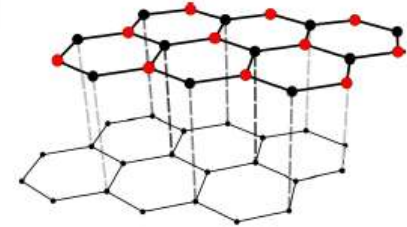




# Thermal Management Techniques

## Graphite Heat Spreaders

- The highly anisotropic thermal conductivity of natural graphite implies that a graphite sheet can function as both a heat spreader and an insulator. It can be used to eliminate localized hot spots in electronic components resulting from uneven loading, surface distortion and uneven heat distribution on the die surface.
- Natural graphite matches the thermal performance of copper in two directions at 15-22% of the weight. The material is suited in a variety of heat spreading applications where in-plane thermal conductivity dominates.
- Advances in graphite based spreader products have lead to pyrolytic graphite sheets comprising of highly oriented polymers with thermal conductivity reaching 1750 W/mK (~ 4 times more than copper). The cost of these products does however increase with the higher thermal conductivity and can be prohibitive for applications requiring a large surface are to be covered
- Lamination, molding and embossing methods can be employed to produce a variety of different component forms. Also, because of their flexibility, natural graphite materials are able to conform well to surfaces under low contact pressures. This combination of properties makes natural graphite a potential substitute for aluminum and copper materials as heat spreaders
- The other potentially attractive feature of natural graphite is that its high specific surface area results in very high electromagnetic interference shielding over the frequency range of 1-2 GHz.





# Thermal Management Techniques

## Graphite Heat Spreaders Application Guidelines

Recommended to use graphite to increase the effective surface area of the heat source and to move heat from a heat source to a heat sink. The customer design will be more thermally effective if the heat sink is able to shed heat to the environment.

### Mechanical Considerations

- Graphite should not be used as a structural material. It will not stand up to lateral, shearing, or torque forces. Graphite has negligible thickness reduction due to compression
- Flexible graphite must be mechanically secured to a structure -- either within a structure (i.e. between rigid layers) or via a fastener such as adhesive or thermal gap pad
- The spreader could be designed to lie on top of the components and held in place by the contact pressure generated by the case maximizing the thermal attach area
- The application must be environmentally evaluated for vibration and temperature to determine the proper mechanical fastening to ensure the heat spreader maintains contact for the life of the product

### Modeling Considerations

- Graphite thickness is to be used as the input to any thermal model and the spreader thickness (graphite thickness plus coating thicknesses) should be used
- Typically graphite spreaders have a PET film affixed to their surface to provide electrical insulation. Studies have shown that contact resistance of the PET layers does not have a significant effect on the performance of the spreader



# Thermal Management Techniques

## Graphite Heat Moving Ability - Thermal Spreading Coefficient

To judge the relative “heat moving ability” of a piece of graphite, of unit width and unit length, to another, we use the concept of the Thermal Spreading Coefficient,  $C_s$ . To determine  $C_s$ , multiply the thermal conductivity of the graphite by its thickness.

$$C_s = k * Thickness$$

This results in a metric that gives the ability of a piece of graphite to move heat. By comparing this to another grade of graphite, the relative ability of two grades of graphite to move heat can be evaluated.

**Example:** Which grade of graphite heat spreader can move more heat - SS400-0.51 or SS300-0.94?

$$C_{S(SS400-0.51)} = \frac{400W}{mK} 0.51mm \left( \frac{1m}{1000mm} \right) = 0.204 \frac{W}{K}$$

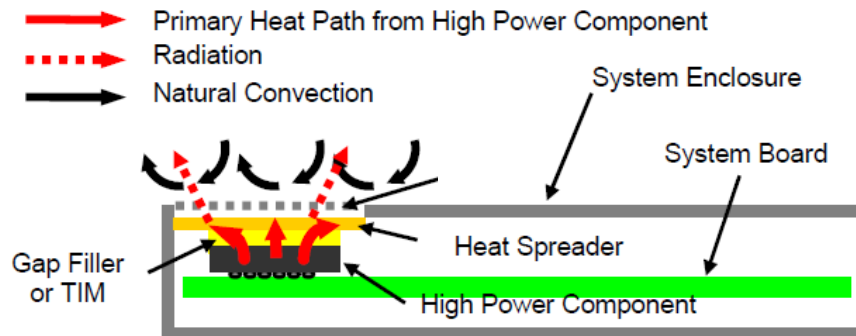
$$C_{S(SS300-0.94)} = \frac{300W}{mK} 0.94mm \left( \frac{1m}{1000mm} \right) = 0.282 \frac{W}{K}$$

This means that SS300-0.94 of a given width and length can move more heat than SS400-0.51 of the same width and length.



# Thermal Management Techniques Enhancing Natural Convection

- The heat dissipated by the device is typically conducted through the polymeric thermal gap filler or thermal interface material (such as thermal grease or elastomer) to thermally conductive heat spreader which has larger surface area where the heat can spread out effectively
- Then heat transfer occurs between the heat spreader and surrounding ambient via natural convection and radiation. The thermally conductive heat spreader can be directly exposed to outside ambient through perforated skin area on the system enclosure case.
- This design concept significantly increased the power dissipation capability, by reducing overall system thermal resistance.
- Adding the metal fins on the heat spreader (to form a heat sink) will provide additional thermal benefit by enlarging participating surface area. (This may not be feasible in low profile form factors of some of the handheld devices)





# Thermal Management Techniques

## Better Enclosures

- The thermal benefit from the use of a gap filler is significantly limited by the heat spreading capability of the system enclosure
- The use of thermally conductive system enclosure results in better thermal dissipation capability
- Magnesium Alloy (AZ91D) often used in enclosures has a low thermal conductivity compared to other materials as shown in the table below.
- Changing to another material with higher thermal conductivity may be an expensive option hence other less expensive alternatives are presented
- Use of heat shields and aluminum/copper backing plates to act as at heat sink could also aid in thermal dissipation of the system enclosure

k	Direction (Planes x,y,z)	Natural Graphite	Magnesium Alloy (AZ91D)	Aluminum 1100 Alloy	Copper
Thermal Conductivity (W/mK)	x,y	140 -1700	72	220	400
Thermal Conductivity (W/mK)	z	3- 10	72	220	400



# Thermal Management Techniques

## Component Placement

- Designers also need to consider the impact of other components on the system board due to their heat generating capacity
- Board population density influences thermal performance of the package and should be modeled accordingly. If the devices are very close the power consumed should be part of the thermal design power budget that needs to be modeled
- PCB's with a high density of high power component population experiences a significantly higher rise in temperature relative to the board being populated with a single high power component
- Some heat generating devices have to be in close proximity to each other for signal integrity and layout concerns such as the DDR memories hence there is no easy solution around this problem
- Designers should however, consider all components and evaluate their placements on the PCB and location with respect to the final form factor housing. Ideally high power devices should not be placed in close proximity to ensure effective thermal dissipation
- Details of such placement recommendations are not in the scope of this report however please refer to examples of component placements in **Appendix E**



# Thermal Management Techniques

## Board Design

Typically more than 80% of the heat generated by a high power component is dissipated through the system board, when no thermal solution is implemented on the top of the package. This indicates that the primary heat path is from junction to the board

### Under-fill

- It is common industrial practice doing under-fill for the key components in to improve the mechanical strength.
- Further thermal improvement can be achieved using the board level under-fill by reducing junction-to board thermal resistance

### Increased PCB Metallization

- Increase the heat dissipation (reducing thermal resistance) can also be achieved by increasing the metallization in the system board. Copper ground layers should be added as part of the board thermal solution.
- Details are provided on the PCB stack up of the Freescale SDP Board used in thermal simulations in the next section of this document

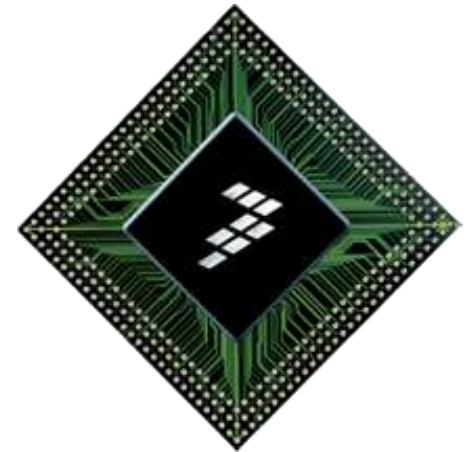
### More Thermal Attach Points

- Special care should also be taken in design PCB thermal attach points which allow heat from the high power component or attached heat spreader to be effectively dissipated.
- EMI shields are often used for thermal attach points to the PCB



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# i.MX 6Dual/6Quad Thermal Characteristics

Table of Thermal Resistance Data



**Device: i.MX 6Dual/6Quad**  
**Package: 625 21 x 21 mm FC-PBGA**  
**Pitch: 0.8 mm**  
**Die Size: 7.2 x 7.2 mm**

Rating	Board Type	Symbol	No Lid	Lid	Unit
Junction to Ambient Natural Convection	Single layer board (1s)	R $\theta$ JA	31	24	°C/W
Junction to Ambient Natural Convection	Four layer board (2s2p)	R $\theta$ JA	22	15	°C/W
Junction to Ambient (@200 ft/min)	Single layer board (1s)	R $\theta$ JA	24	17	°C/W
Junction to Ambient (@200 ft/min)	Four layer board (2s2p)	R $\theta$ JA	18	12	°C/W
Junction to Board		R $\theta$ JB	12	5.0	°C/W
Junction to Case (Top)		R $\theta$ JCtop	< 0.1	1.0	°C/W

1. Junction-to-Ambient Thermal Resistance determined per JEDEC JESD51-3 and JESD51-6. Thermal test board meets JEDEC specification for this package.
2. Junction-to-Board thermal resistance determined per JEDEC JESD51-8. Thermal test board meets JEDEC specification for the specified package.
3. Junction-to-Case at the top of the package determined using MIL-STD 883 Method 1012.1. The cold plate temperature is used for the case temperature. Reported value includes the thermal resistance of the interface layer.

**Refer to the i.MX 6Dual/6Quad Applications Processors datasheet for the latest thermal characteristics**



# Thermal Models

- A validated thermal model – both at system and package levels – can significantly reduce the thermal design cycle and time-to-market
- The customer must create system level simulations to gain more accurate thermal results for the application setup

## Package Model

- From a package perspective the model requires four blocks: die, solder/underfill, substrate, and solder/air.
  - The solder/underfill and solder/air require orthotropic material properties because the conductivities are direction dependant.
  - In the out-of-plane direction (z-axis) the solder balls increase the conduction through these layers.
  - In the in-plane (x-axis and y-axis) direction the bulk conductivities of the underfill or air dominate.
- The solder/air layer would be modeled with the same footprint as the substrate
- The solder/underfill layer would be modeled the same size as the die
- The other two volumes, exposed die and substrate, have isotropic material properties



# Thermal Models

- Heat is generated in the circuitry, which is located at the Silicon (die) to Underfill interface. The heat travels along two principal paths:
  - Top of the die or
  - Substrate into the printed circuit board (PCB)
- Heat is then removed from all exposed surfaces by convection and radiation.

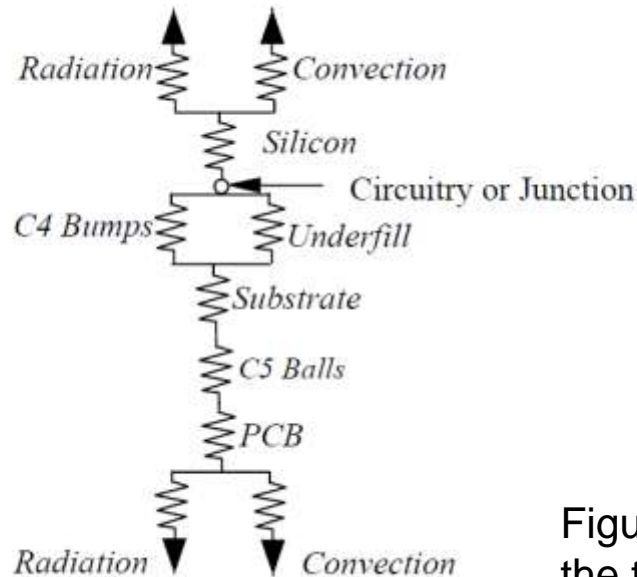
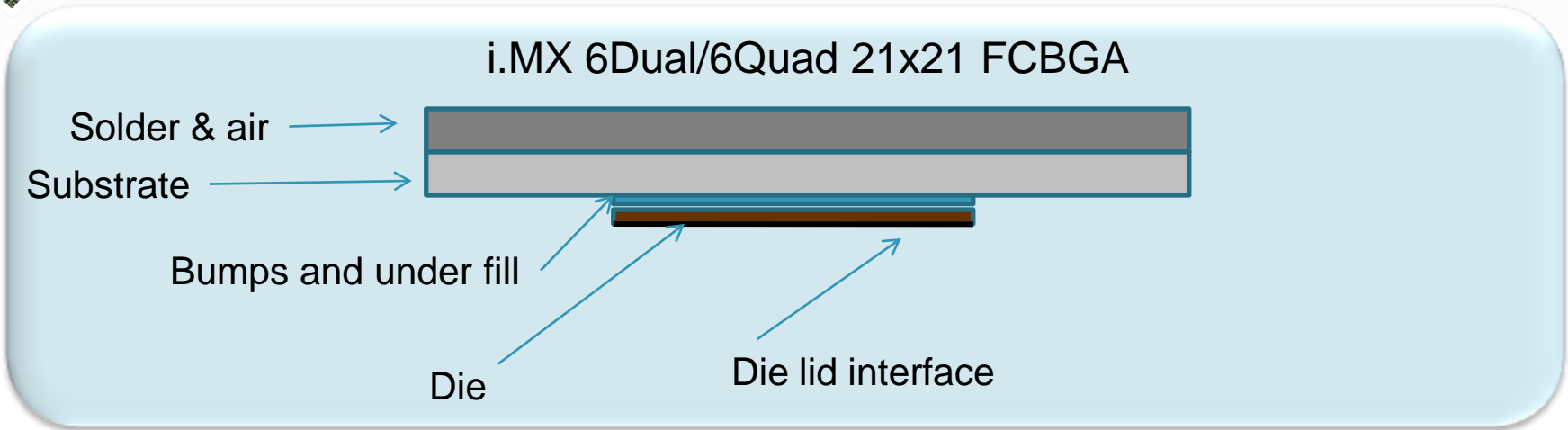


Figure shows a representation of the three-dimensional heat path



# i.MX 6Dual/6Quad Thermal Models



## Thermal Conductivity

Component	Material	Kx [w/m*k]	Ky [w/m*k]	Kz [w/m*k]
Die lid interface	Compound	2	2	2
Die	Silicon	117	117	117
Bumps and underfill	Compound	0.6	0.6	5.3
Substrate	Compound	33	33	0.8
Solder and air	Compound	0.034	0.034	13.9





# Thermal Models

## Thermal Modeling

Thermal models can be created which can account for the following system attributes:

- Board size and Enclosure dimensions and materials
- Boundary & environmental conditions (natural convection and forced convection)
- Heat spreaders and lid materials (Al, Cu, Graphite or Ceramic)
- Interface materials (DowCorning 1-4174)
- Heat sinks

## Thermal Modeling Tools

Thermal simulation tools can be used to provide IC thermal models that can be integrated with product thermal models to obtain a complete system model. The primary thermal modeling tools used by Freescale are listed below:

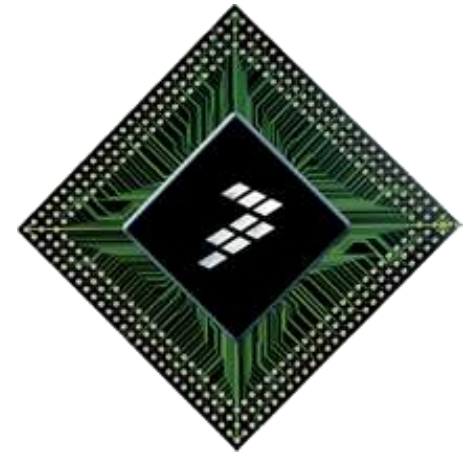
- ANSYS Icepak
- Mentor V3.2 FloTHERM 9.2

Thermal Models for i.MX 6Dual/6Quad SoC can be made available on request.



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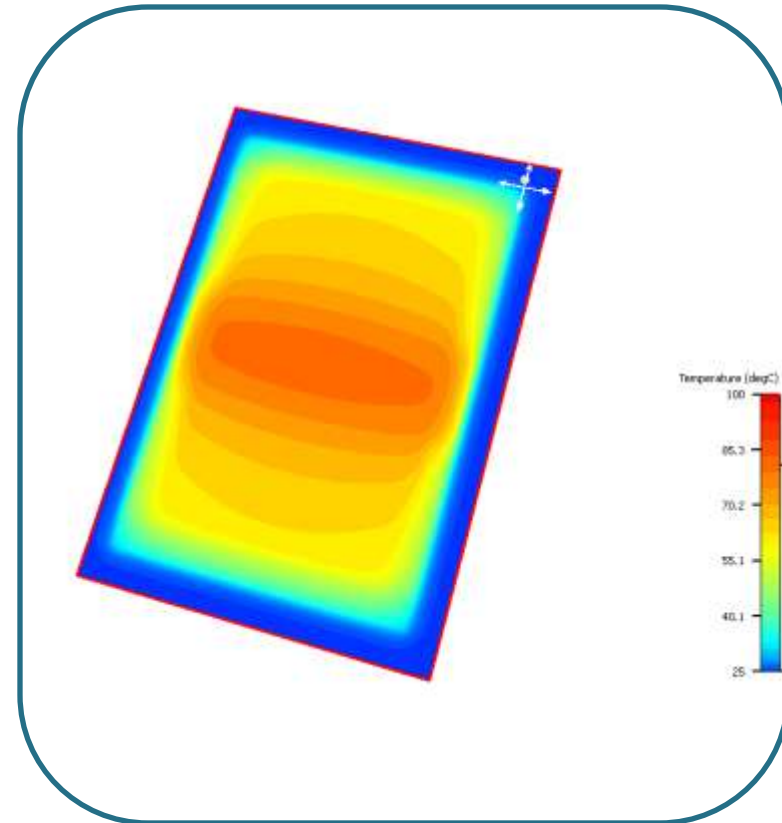




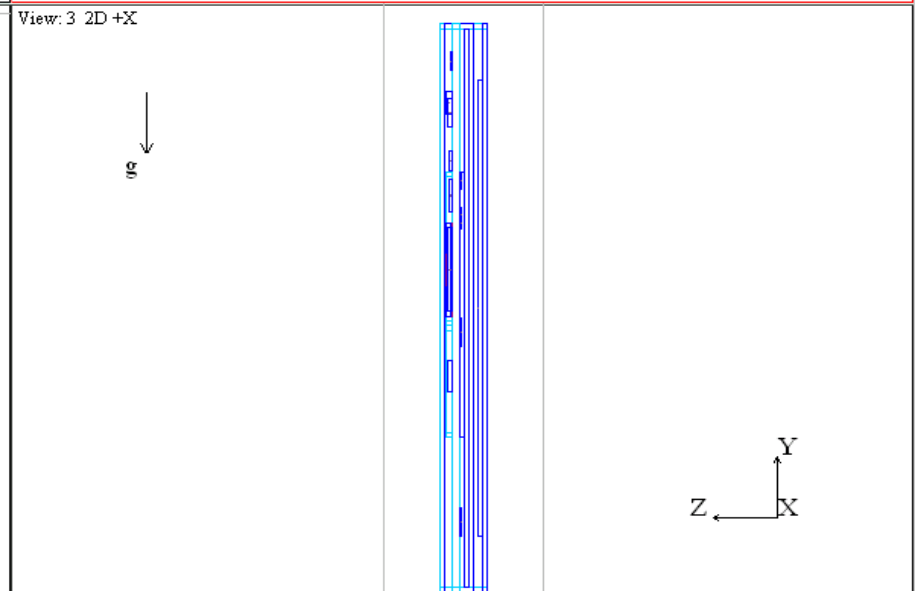
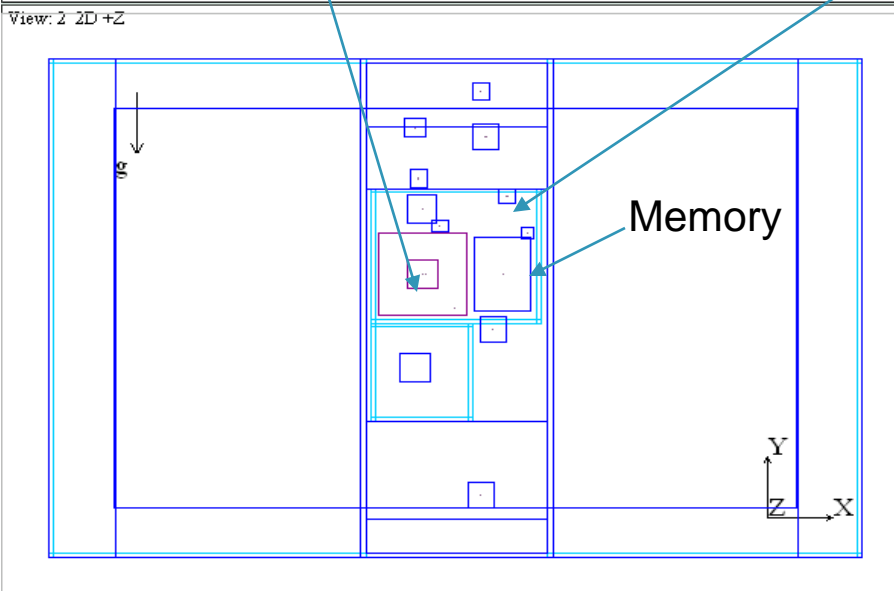
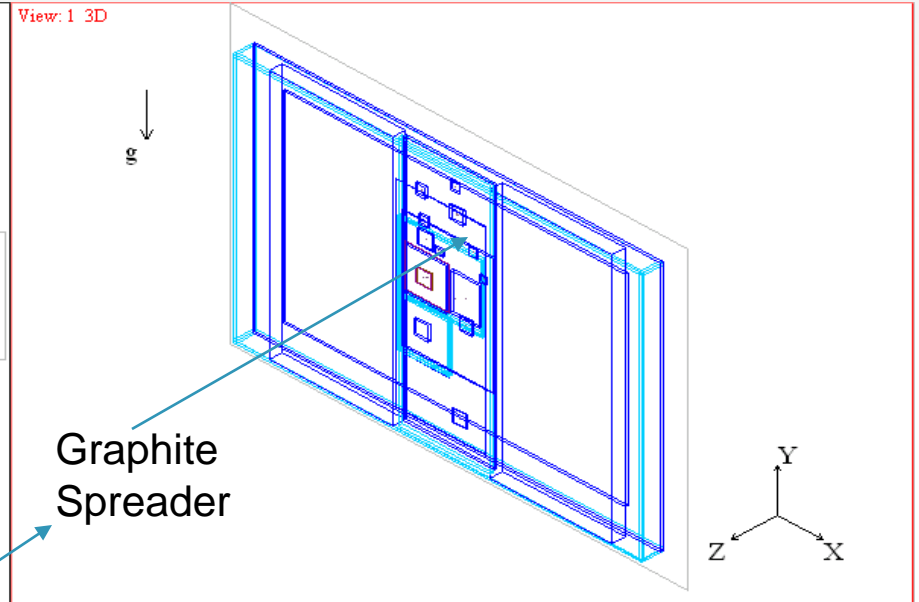
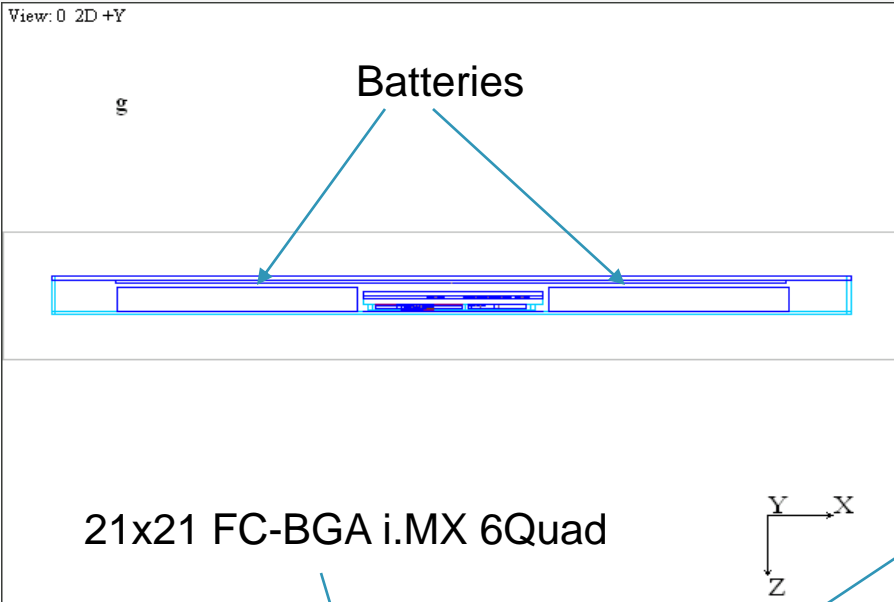
# i.MX 6Dual/6Quad Thermal Simulations

This section provides a summary of the thermal simulations performed on an example tablet model. The intent of the simulations are to illustrate some of the thermal management techniques detailed in the previous sections.

- Although this particular tablet simulation may not fit all customer applications, it does demonstrate the benefits of various thermal solutions and guidelines on when such solutions are required
- Freescale recommends that customers should perform system level simulations to gain more accurate thermal results for their specific application
- The simulation results use the i.MX 6Dual/6Quad 21x21 FCBGA in both the non-lidded and the lidded package
- To better account for customer application use cases the simulation results also included other high power heat generating components such as the DDR3 memory and the LCD
- Simulations were limited to use cases of continuous 2W and 5W power consumption by the i.MX 6Dual/6Quad SoC



# Geometry of Simplified Thermal Model





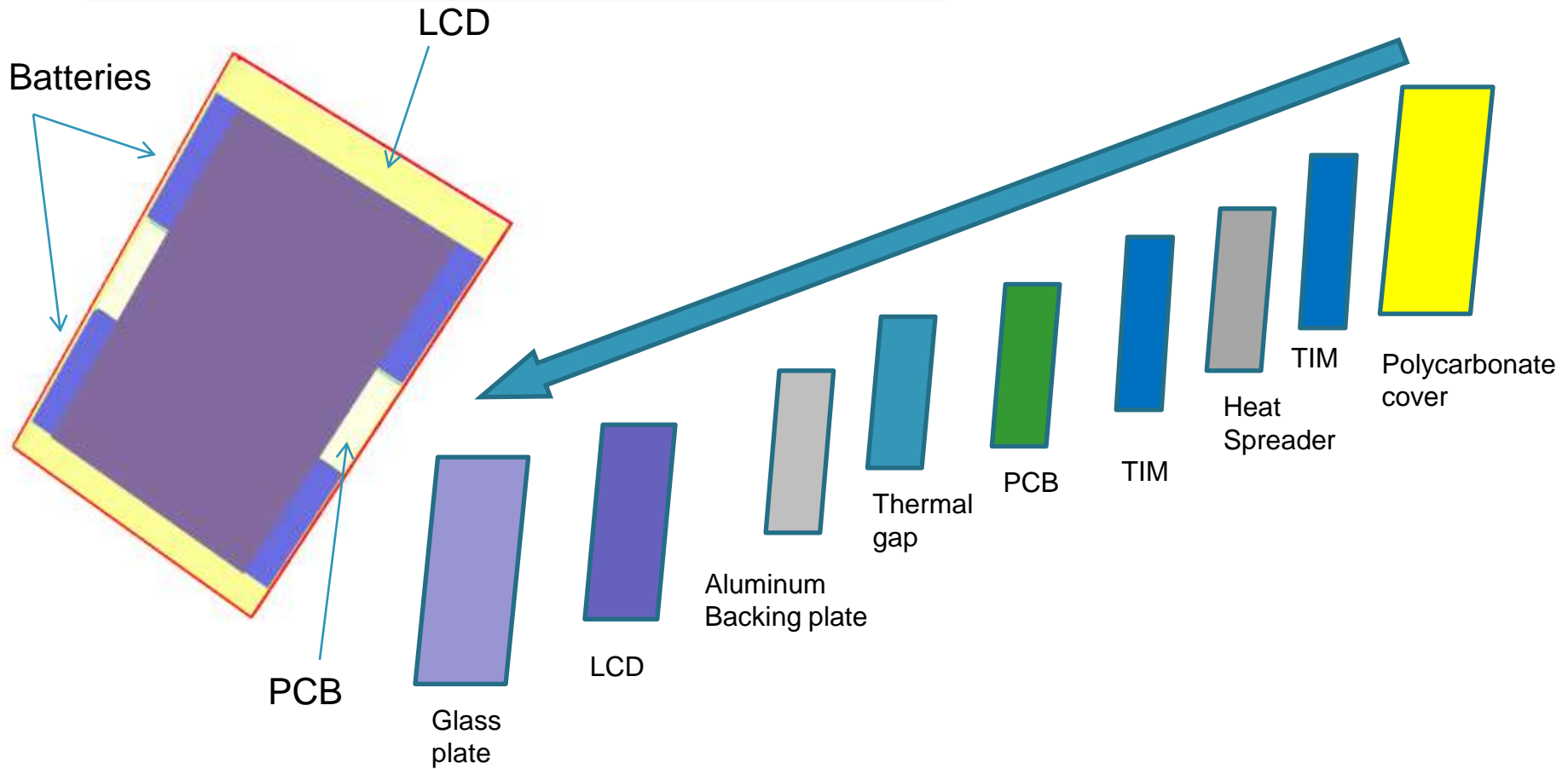


# Thermal Simulation Details

Simulation Attribute	Simulated Value
Enclosure Dimensions [mm]	220x150x20
System Orientation	Horizontal (Normal to Z-direction)
Gravity	9.81 m/s <sup>2</sup> , Negative Z direction
Simulated Heat Transfer Modes	Steady-state, Convection, Conduction, Radiation
Ambient condition	25C, Atmospheric pressure
PCB Dimensions [mm]	127x43x1.6
Box size [mm]	191x127x10
Air Flow velocity	Natural Convection
Thermal Model	Tablet thermal model using the Freescale SDP PCB board (8 Layers) and components including DDR3 memory and LCD display
Main Processor	i.MX 6Dual/6Quad 21x21 FCBGA in both the non-lidded and the lidded package

# System Components

Tablet model showing various system components that were included in the thermal analysis





# System Components

Table model showing thermal conductivity of various system components that were included in the thermal analysis

Item	Components	Material	Thermal Conductivity (W/m K)		
			X	Y	Z
Enclosure		Polycarbonate	0.2	0.2	0.2
Battery		Compound	20	20	20
PCB		Compound	Calculated	Calculated	Calculated
i.MX 6Dual/6Quad					
	Solder and air	Compound	0.034	0.034	13.9
	Substrate	Compound	32.9	32.9	0.81
	Bump & Underfill	Compound	0.6	0.6	5.3
	Die	Silicon	117	117	117
	Die lid interface	Compound	2	2	2
	Lid	Copper	389	389	389
Spreader		Copper/Graphite	389/600	389/600	389/3.5
TIM		Compound	16	16	16
LCD					
	LCD screen	Glass	1	1	1
	LCD circuit	Compound	125	125	125
Glass plate		Glass	1	1	1
Thermal gap pad		Compound	2.4	2.4	0.6
Backing plate		Aluminum	201	201	201



# Simulation Details

## PCB Components and Stack Up

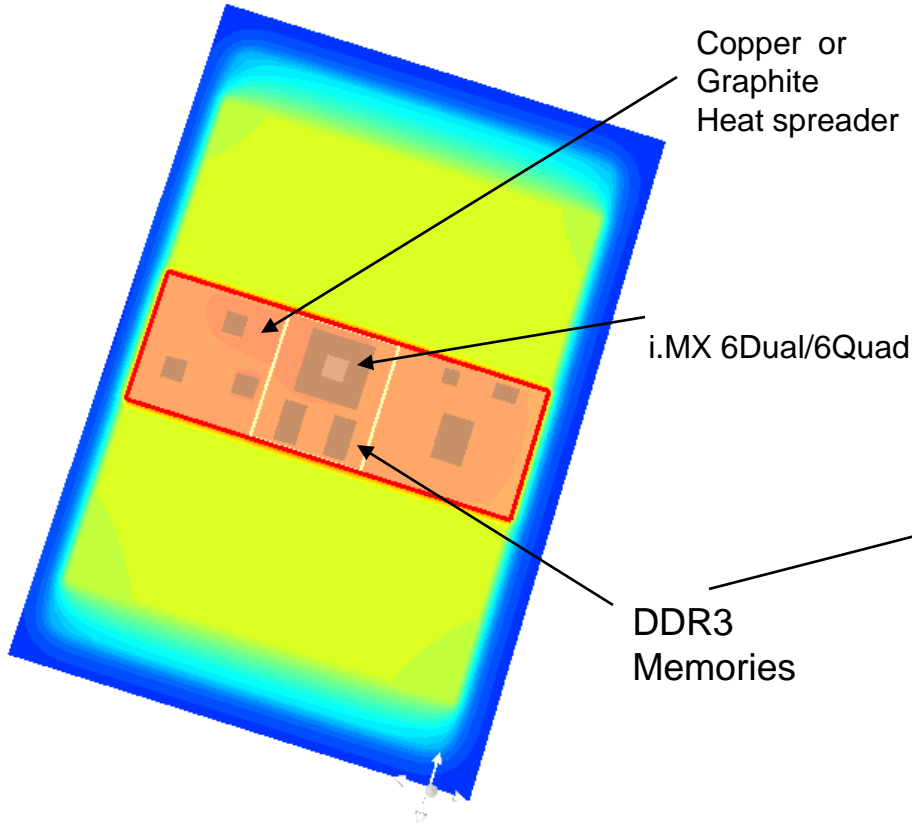
Power consumption of components on Freescale SABRE SDP board, Rev B

Additional power source : LCD screen – 3W

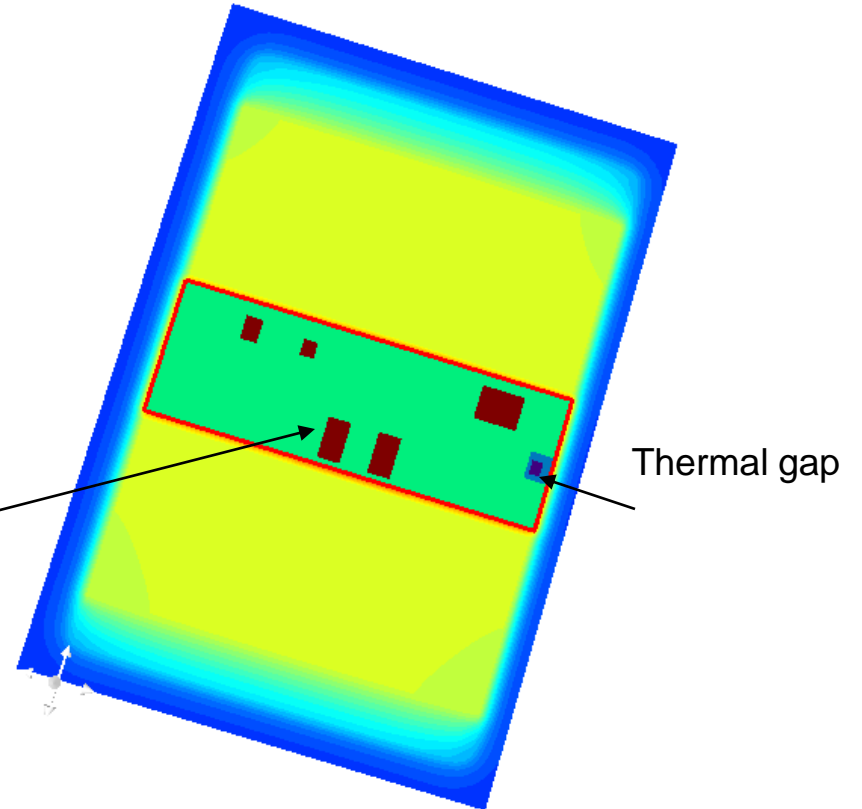
#	Part	Assembly name	Location	Power [W]
1	IMX6	U1	Up	5W and 2W
2	DDR x 4	U2,U3,U4,U5	Up/Down	0.26
3	QFN5X3	U18	Up	0.0015
4	QFN56	U8	Up	0.1
5	XTAL	Y500	Down	0.01
6	MODULE_AH	U19	Up	0.15
7	QFN48	U516	Down	0.08
8	BGA196	U512	Down	0.66
9	BAROMETER	U21	Up	0.005
10	MAX8903	U502	Down	0.25
11	MAX8815	U6	Up	0.25
12	Compass	U20	Up	0.001
13	PMIC	U8	Up	0.5

PCB Stack Up			
Layer	Type	Thickness (mil)	
	Top	Solder Mask	0.50 mils
L1	TOP	copper+plating	1.78 mils
		dielectric thickness	3.50 mils
L2	GND Plane 1	copper	1.30 mils
		dielectric thickness	6.00 mils
L3	Internal 1	copper	1.30 mils
		dielectric thickness	6.50 mils
L4	Power 1	copper	1.30 mils
		dielectric thickness	18.00 mils
L5	Power 4	copper	1.30 mils
		dielectric thickness	6.50 mils
L6	Internal 2	copper	1.30 mils
		dielectric thickness	6.00 mils
L7	GND Plane 2	copper	1.30 mils
		dielectric thickness	3.50 mils
L8	Bottom	copper+plating	1.78 mils

## PCB Top View



## PCB Bottom View



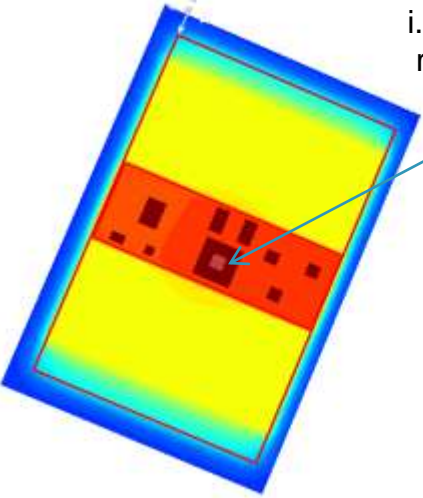


# Thermal Simulation Results

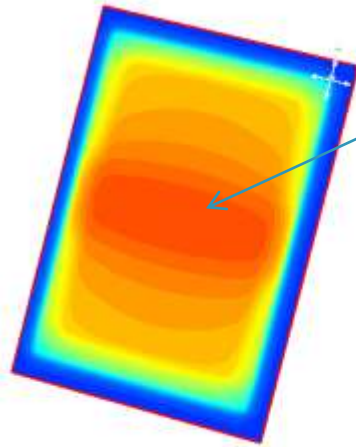
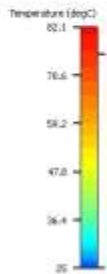
## Simulated i.MX 6Dual/6Quad Power

**Power = 2 W**

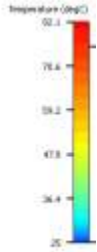
Note : Colors denote the relative temperature and not absolute



i.MX 6Dual/6Quad reaches a temperature of 80 ° C

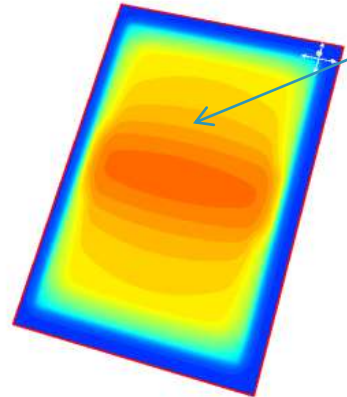
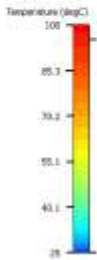
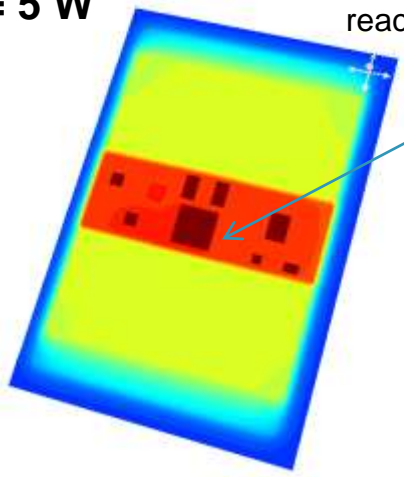


LCD Temp 70 ° C

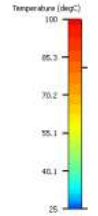


**Power = 5 W**

i.MX 6Dual/6Quad reaches a temperature of 100 ° C



LCD Temp 80 ° C





# i.MX 6Dual/6Quad Thermal Simulation Results

## Heat Spreader Advantages

The goal of these simulations was to determine what is the maximum processor power to maintain 85Deg C within the enclosure and  $\leq 105\text{Deg C } T_j$  on the die, with different thermal management techniques applied. Various models were created that varied the package lid options as well as the heat spreader to be used in the tablet.

i.MX 6Dual/6Quad Package Configuration	Heat Spreader Option (Assumes entire PCB dimension coverage)	Max Power (W) (To maintain 85Deg C within the enclosure and $\leq 105\text{Deg } T_j$ on die)
Un-lidded	None	2.3
Lidded	None	3.5
Un-lidded	Graphite (eGraph SS600 0.127mm, TIM K = 2 W/m K )	3.6
Un-lidded	Graphite (eGraph SS500 0.127mm, TIM K = 17 W/m K )	5.6
Un-lidded	Copper (0.2 mm, TIM K = 17 W/m K )	4.6
Un-lidded	Copper (0.6 mm, TIM K = 17 W/m K )	5.7

The results show that using a heat spreader increases the thermal design power and hence allows running higher power consuming applications within the same thermal envelope



# i.MX 6Dual/6Quad Thermal Simulation Results

## Heat Spreader Dimensions

The goal of these simulations was to determine what is the maximum processor power with different heat spreader dimensions to be used in the tablet. The table below shows results of different heat spreaders with varying dimensions including the spreader thickness. The TIM used had a thermal conductivity  $K = 17 \text{ W/m K}$

Heat Spreader Options	Max Power (W) (To maintain 85Deg C within the enclosure and $\leq 105\text{Deg Tj}$ on die)		
	30% PCB Coverage Spreader dimensions: 43x37mm	55% PCB Coverage Spreader dimensions: 43x71mm	100% PCB Coverage Spreader dimensions: 43x127mm
<b>Graphite</b> (eGRAF SS500 Thickness : 0.6mm, TIM $K = 17 \text{ W/m K}$ )	4.0	4.7	5.6
<b>Graphite</b> (eGRAF SS400 Thickness : 0.6mm, TIM $K = 17 \text{ W/m K}$ )	4.0	4.7	5.6
<b>Copper</b> ( $K = 389$ Thickness : 0.6mm, TIM $K = 17 \text{ W/m K}$ )	3.9	4.5	5.7
<b>Copper</b> ( $K = 389$ Thickness : 0.2mm, TIM $K = 17 \text{ W/m K}$ )	2.9	3.7	4.6

**The results show that increasing the heat spreader coverage and thickness increases the thermal design power and hence allows running higher power consuming applications within the same thermal envelope**





# i.MX 6Dual/6Quad Thermal Simulation Results

## Thermal Interface Material Selection

The goal of these simulations was to determine what is the maximum processor power with different thermal interface materials to be used in the tablet. The table below shows results of different heat spreaders with varying dimensions including the spreader thickness

Thermal Interface Material (TIM)	Max Power (W) (To maintain 85Deg C within the enclosure and <=105Deg Tj on die)		
	30% PCB Coverage Spreader dimensions: 43x37mm	55% PCB Coverage Spreader dimensions: 43x71mm	100% PCB Coverage Spreader dimensions: 43x127mm
TIM K = 2 W/m K (eGRAF SS500 Thickness : 0.6mm)	3.8	4.4	5.2
TIM K = 2 W/m K (eGRAF SS400 Thickness : 0.6mm)	3.8	4.4	5.1
TIM K = 17 W/m K (eGRAF SS500 Thickness : 0.6mm)	4.0	4.7	5.6
TIM K = 17 W/m K (eGRAF SS400 Thickness : 0.6mm)	4.0	4.7	5.6

The results show that increasing the thermal conductivity of the TIM does marginally increase the thermal design power which is aided by increased thermal conductivity and dimensions of the heat spreader



# Thermal Interface Comparisons

Double Sided adhesive tape



Double faced adhesive tape is not an effective thermal interface

Thermally Conductive Silicone



Red Copper: 401W/(m·K)



Thermally Conductive Silicone is a better interface medium resulting in lower temperatures similar to the lidded package

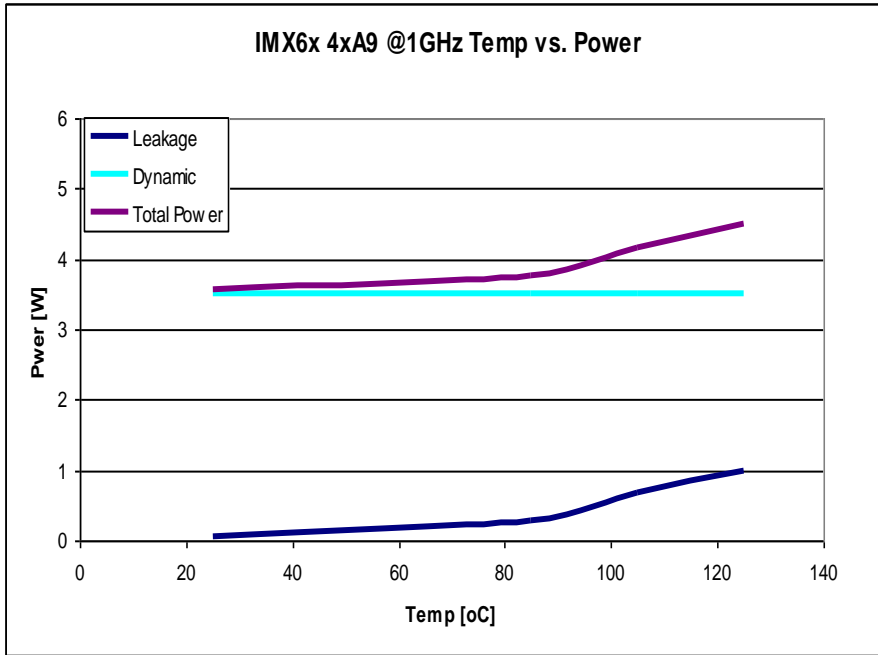
For the same use case run on the Freescale i.MX6Q SD REVB board the lid temperature was approximately 10 degrees cooler using the higher thermal conductivity thermal silicone grease than the double faced thermal adhesive tape



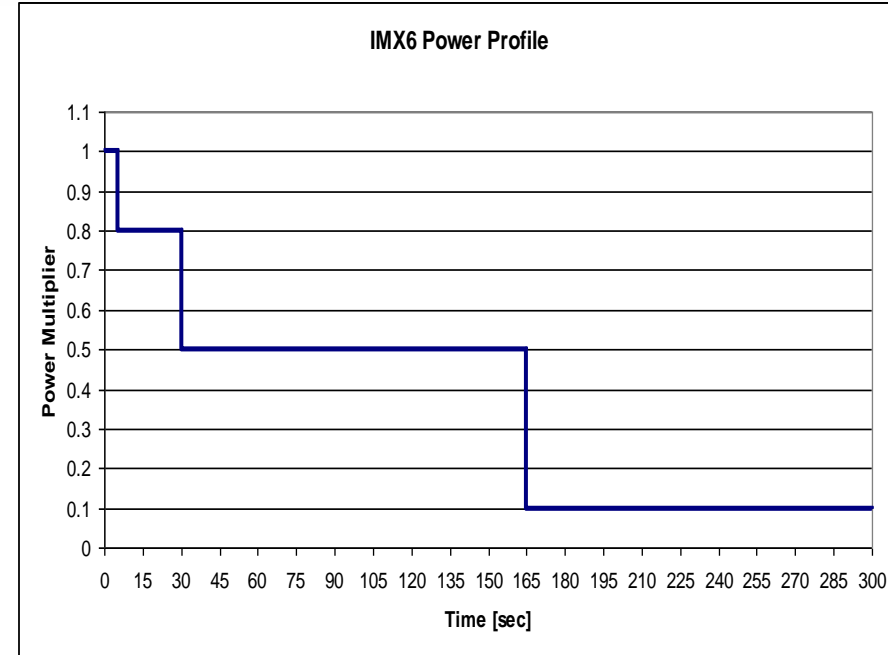
# i.MX 6Dual/6Quad Thermal Simulations

## Power Transient Profile

### Power Vs. Temperature



### Power Profile



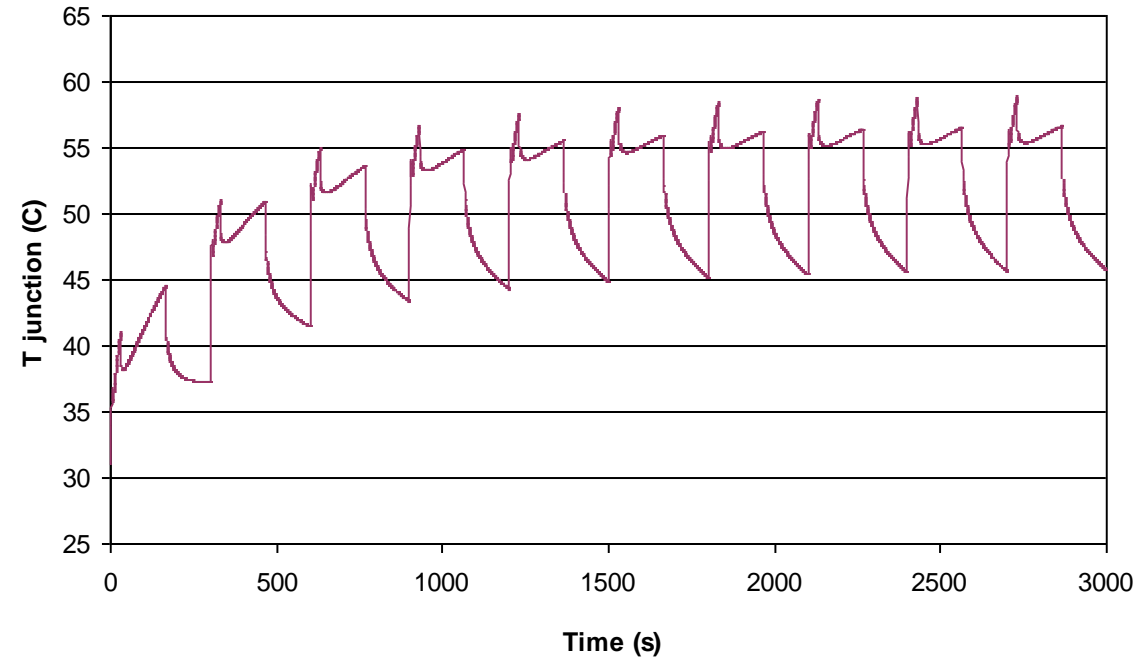
Additional simulations were performed with the Tablet model using an example power profile. This was used to prove that short bursts of intensive processing followed by long intervals of the in idle can automatically regulate the heat without much external intervention.

Other power contributors : PCB – 1.5W constant, 7” LCD – 1W constant, LPDDR (max power)– 0.65W

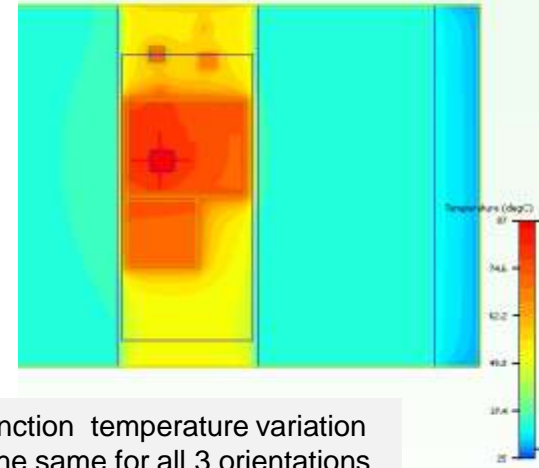
# i.MX 6Dual/6Quad Power Profile Junction Temperature Variation with Time

T ambient = 25 C

Tablet Model



Tj (imx6x)



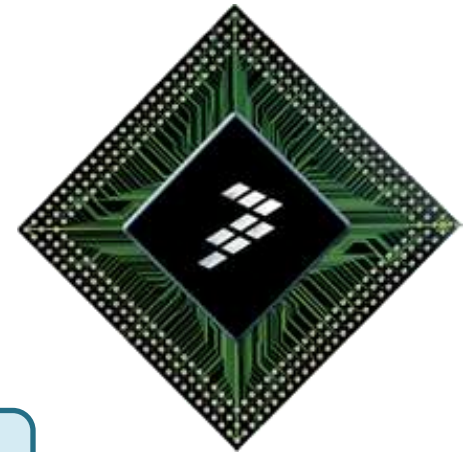
Junction temperature variation is the same for all 3 orientations (gravity in negative x, y, and z directions)

Example Duty cycle considered:

- 5s at max power, 25s at of 80% of max power, 135 s at max power/2 and 135 s at low power
- System eventually reaches a steady state over time



- Overview
- Thermal Management Concepts
- Thermal Attributes
- Thermal Simulations
- **Software Thermal Management Techniques**
- Recommendations /Conclusion
- Appendix/References





# Software Thermal Management Techniques

The i.MX 6 series and the i.MX 6Dual/6Quad SoC in particular incorporates several low-power design techniques, to meet requirements of low-power design, while sustaining high performance operation when required. Even with these techniques in place managing the heat dissipated needs to be considered depending on application use case. The more intensive the use case with all major power contributors active such as the Cortex A9 cores, Graphics Processing Unit (GPU) and the DDR memories the higher the potential thermal energy that needs to be effectively dissipated.

## Software Leverages Hardware

Leveraging features and power saving strategies implemented at the device and micro architectural level can have a significant impact on thermal demand. Software can take advantage of various hardware features that allow power optimization thereby managing heat dynamically and reducing the need for heat spreaders, heat sinks and metal enclosures.

This section focuses specifically on ways to improve thermal performance in by limiting the source of heat in integrated circuits: power. Although a deep dive into these features are beyond the scope of this report a few key aspects of chip level power and software thermal management techniques will be discussed in this section of the document.



# i.MX 6Dual/6Quad Software Thermal Management

Technique	HW Support	BSP Support	Comments
DVFS	Yes	Yes Feature implemented in BSP version GA1209	Pre defined set points defined for frequency and Bus Scaling
Temperature Monitor	Yes	Yes Feature implemented in BSP version GA1209	Define thresholds based on temp sensor readings
Temperature Aware DVFS	Yes	Yes Feature implemented in BSP version GA1209	Throttle CPU based on temp sensor readings
Temperature Aware CPU Pool Management	Yes	No Feature to be implemented in future BSP release	Offline cores is not supported in current BSP release
Clock & Power Gating	Yes	Yes Feature implemented in BSP version GA1209	Gate clocks and power domains when not in use
DDR (MMDC) and I/O Power Optimizations	Yes	Yes Feature implemented in BSP version GA1209	Optimized ODT settings, Auto power down modes and support for frequency scaling
GPU Power Management	Yes	No Feature to be implemented in future BSP release	Reduce Core clock frequency, reducing shader clocks
LDO Full Bypass	Yes	Yes Feature implemented in BSP version GA1209	Bypass LDO and use external PMIC.

For full power management features supported please refer to the table in Appendix B



# Linux Power Management Features

The architecture for power management on i.MX processors is largely driven by the underlying power management framework within operating systems such as Linux. The Linux power management architecture can be separated into separate frameworks for the CPU and peripherals. The CPU feature mapping is shown below:

## CPU Power Management

Feature	Linux BSP Mapping
CPU SMP Workload Management	Linux Scheduler <ul style="list-style-type: none"> <li>• Thread Affinity</li> <li>• Load Balancing (SCHED_MC)</li> </ul>
CPU Operating States (run, idle, suspend)	CPUidle PM Core
OS Tick Suppression	Kernel CONFIG_NO_HZ
CPU Pool Management	CPU hotplug
CPU Frequency and Voltage Scaling	CPUfreq
Thermal Management	CPU hotplug CPUfreq





# Memory Controller (MMDC) Optimizations

## (Included in BSP Version GA1209)

- When possible, at lower performance use-cases, users should switch to DDR3: DLL off mode, which allows to greatly reduce the DDR frequency and thus disable or reduce termination and reduce the drive strength, which significantly reduces the power consumption of the DDR interface.
  - Note : Support for drive strength reduction in DLL OFF mode is not supported in the BSP*
- Transitions between DDR modes such as frequency changing add extra cost and power. Slowing requesters while keeping DDR at full speed may increase total system power.
- Cooperative Dynamic Frequency Scaling is implemented in order to keep the system “balanced” i.e. keep system in balance when DDR throughput is equal or slightly higher than total amount of requests generated by all requesters.
- Reducing the DDR frequency, while in DDR3: DLL-ON mode may be not efficient, because:
  - Reduction in DDR frequency will cause bus duty cycle to increase and thus reduces chance of automatic MMDC power saving (place memory into Self Refresh).
  - Total amount of read/write operation does not change (power is per-operation)
  - The termination is active longer, though, lowering frequency from 528Mhz to 400MHz or below may enable lowering drive strengths and termination
- A good strategy for many types of workload is to combine most activity in bursts (natively possible, for example, for typical multimedia applications, communication, etc.) and run this segment at maximal speed and then switch to DDR3: DLL-OFF mode to support “background activity” (communication, display refresh, etc.)



# DDR I/O Power Management

## (Included in BSP Version GA1209)

### On Die Termination

The DRAM Interface power dissipation depends on many variables however proper termination and drive strength is key for power and thermal performance. Memory and controllers provide a host of programmable options for the drive strength of the output buffers and for the on-die termination impedance.

- The ideal settings for drive strength and ODT will also depend on the clock frequency to ensure that inter-symbol interference (ISI) effects are not introduced
- An optimized system creates smaller reflections, cleaner edge transitions and overall lower power dissipation
- DDR3 PHY power dissipation decreases significantly as the ODT termination values programmed into the DDR SDRAM are increased
- DDR PHY power is also proportional to bus activity and what type of activity is happening on the bus (e.g., Read, Write or idle)
- Due to the ODT that is active in the DDR PHY during Reads from the DDR SDRAMs, DDR PHYs typically consume more power during a Read versus a Write when the data is driven off-chip to the DRAMs.
- For more data on ODT savings please refer to the Application note AN4509 i.MX 6Dual/6Quad Power Consumption available on the Freescale Extranet.



# DDR I/O Power Management

(Included in BSP Version GA1209)

- ODT settings shown below:

Register Setting (MPODTCTRL)	DDR_ODT (Ohms)	IMX_ODT (Ohms)	Comments
0x22227	120	060	Highest Power consumption
<b>0x11117</b>	<b>120</b>	<b>120</b>	<b>Recommended</b>
0x00007	120	000	Use only if validated on Board
0x00000	000	000	Not Recommended

- The highlighted row shows the Freescale recommended ODT setting of 0x11117 that is programmed in the MMDC MPODTCTRL register
- 0x00007 can save about 40% DDR power compared to strongest setting(0x22227), but really depends on the customer board layout
- Termination requires a lot of care in component-based, embedded applications
- Freescale recommends signal integrity analysis be performed to determine the optimal output drive impedance and ODT values for the specific customer system



# DDR I/O Power Management

## (Included in BSP Version GA1209)

### Reducing I/O Power

- As we move to wider DDR interfaces with higher clock rates, the power consumed by the DDR I/O continues to grow significantly. By using peripheral DVFS to lower the DDR clock rate to a frequency that adapts to memory bus loading, it may be possible to lower the DDR I/O drive strength at lower frequencies. This particular feature is planned for the next BSP release.
- In other cases where the DDR is placed into self-refresh, the DDR I/O can be floated or lowered to minimum drive allowed by JEDEC.
- Modifying the DDR drive strength must be done by code that is executing from a memory region other than DDR (for example, IRAM).
- No access to DDR (including page table walks, cache misses, alternate bus master accesses) is allowed while the DDR I/O pads are being reconfigured.

### Enabling Auto Power Saving

- Additional power savings can be achieved by enabling auto power saving mode, which will allow the DDR memory to automatically enter self-refresh mode when there are no DDR accesses for a configurable time. The default setting is 1024 clock cycles which can be optimized based on the customer use case and application

### DDR Memory Selection

- Consider LPDDR2 over DDR3. Although LPDDR2 may be at a higher price premium, it draws less power than DDR3 devices. In addition, since LPDDR2 does not have a DLL, eliminating the complexity of managing DDR3: DLL on and off modes for frequency scaling. DDR3L is also an available memory choice for further reducing DDR power consumption.



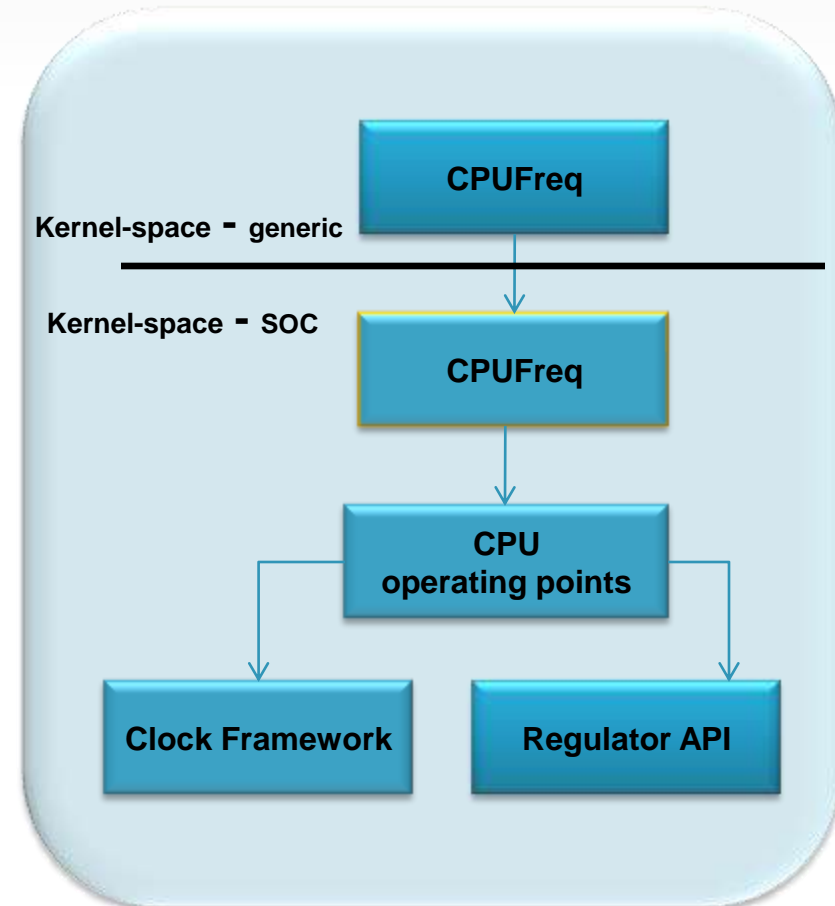
# CPU Freq Mechanism

(Included in BSP Version GA1209)

To use DVFS, pre defined policies are employed that govern when to switch between set points in the application. In the Linux BSP release, there is operating system support for managing DVFS via CPUFreq utilities, and is comprised of a driver and one or more governors. The Linux BSP has a set of governors that can be used to optimize the DVFS subsystem based on the needs of the application.

Example governors exist for *performance*, *power*, *userspace*, and *ondemand*. The *userspace* governor allows applications to control when, specifically, to move between OPPs. The *ondemand* governor scales up when there is high CPU utilization and down when there is low CPU utilization. The *CPUFreq* framework allows applications to subscribe to DVFS change events.

Please refer to the *CPUFreq* section of the Linux kernel documentation for more information.





# CPU Freq mechanism

(Included in BSP Version GA1209)

- The ARM Frequency (*CPUFreq*) interactive governor when enabled will auto scale the CPU frequency according to the CPU loading
- The supported ARM CPU frequency and ARM core Voltage (VDDARM\_CAP) set points are available in the i.MX 6Dual/6Quad Data Sheet:
- Specifically, when the new target frequency is higher (resulting from moving to a higher set point), the voltage is increased first, followed by the core frequency.
- When the new target frequency is lower (resulting from moving to a lower set point), the core frequency is reduced first, followed by the voltage reduction
- To balance the power saving and performance, the interactive governor can act upon the CPU Load. The CPU frequency adjustment is determined by the percentage of CPU loading.

For example, if the CPU loading is about 75%, then the CPU frequency will be

$996\text{MHz} * 75\% = 747 \text{ MHz}$  ,

Hence the CPU freq driver will adjust the ARM core frequency to the 792 MHz set point



# CPU Pool Management

- For multi-core systems such as the i.MX 6Dual/6Quad processors, it is possible to add and remove available cores from the CPU pool
- This CPU pool management was originally designed to allow hot-swapping of CPU boards on multi-core systems without taking the entire system offline
- In embedded systems, cores can be removed from the available CPU pool during periods of low CPU loading or when managing the temperature
- The cores removed from the CPU pool can remain in a low-power state or possibly powered off entirely if the architecture allows
- Aggregating the CPU workload onto fewer cores can reduce overhead associated with threads migrating to different cores and maintaining coherency between the cores
- The Linux BSP mapping of this feature is referred to *CPU Hotplug* and is briefly described in the following section



# CPU Pool Management

## CPU hotplug

- *CPU hotplug* is a Linux kernel framework that places CPU's on/offline
- *CPU hotplug* can be used for power savings
  - The scheduler does not assign processes to CPU offline
  - The scheduler can add or remove CPU's by *CPU Hotplug*
- SCHED\_MC manages the spread of work load among online CPU's
  
- *CPU hotplug* can be utilized for both CPU Pool management as well as Thermal Management
- During system operation as defined thermal thresholds are reached the thermal driver will remove one of the secondary cores
- If the system temperature keeps increasing, the thermal driver will continue to remove additional cores until only the primary CPU0 core is left running
- When the temperature falls back to the safe range, all additional cores that were removed will be brought back online
- **Note:** *CPU hotplug* is not currently supported as a mechanism for thermal management in the current BSP GA release





# BUS Frequency Scaling

(Included in BSP Version GA1209)

- DVFS for ARM and scaling the frequencies of the DDR, AXI, AHB, and IPG bus clocks can significantly reduce the power consumption
- However, due to the reduced operation frequency, the accesses to the DDR take longer, which increases the power consumption of the DDR I/O and memories
- This tradeoff needs to be taken into account for each mode, to quantify the overall affect on system power.
- Algorithms used to scale internal bus frequencies ideally should match the bus bandwidth required for the current use case. In the absence of bus monitors, it may be possible to scale bus frequencies based on the activity of bus masters
- It is also important to determine, if the system is “memory” bounded or “processing” bounded in target use cases and different stages of execution within the use case



# BUS Frequency Scaling

(Included in BSP Version GA1209)

- Enable the BUS freq driver to auto scale the bus frequency utilizing the 4 set points as shown in the table below:

DDR freq (MHz)	AXI (MHz)	AHB (MHz)	Power saved
528	264	132	Full Speed
400	200	133	Mid speed
50 (DLL off)	50	25	Audio bus mode
24 (DLL off)	24	24	Low bus mode

- The BUS freq driver will work in the following manner:
  - If high speed device clocks are enabled, bus frequency scaling not performed and continue to run at full speed;
  - If no high speed devices are enabled, but CPU freq is not at lowest set point, run at mid speed;
  - If no high speed devices are enabled and CPU freq is at the lowest set point, but audio module is enabled, run in the audio bus mode;
  - If no high speed devices are enabled and CPU freq is at the lowest set point, and audio module is not enabled, run in the low bus mode;



# Clock Gating & Power Domain Control

## (Included in BSP Version GA1209)

### Clock Gating

- Maintain clock parent/children dependency in clock tree, all drivers need to disable their clocks when they are not active
- The clock driver framework to auto disable all the clocks whose use count is 0. This ensures all unused clocks are disabled
- If aggressive clock gating is utilized (run-fast-and-stop), then Dynamic Frequency Scaling (DFS) offers little benefit and could actually increase power due to longer bus duty cycles

### Power Gating

- Power gate unused domains under certain use cases, such as the PU domain when system is in low power audio mode and system idle mode
- The GPUs and VPU are part of the PU power domain, which can be powered off by power gating their corresponding LDO. The PU domain is managed by GPU/VPU drivers. Support for this feature is planned for the next BSP Release
- The bus freq driver performs this when migrating into low power audio or system idle modes  
(For a definition of these low power modes please refer to *AN4509 i.MX 6Dual/6Quad Power Consumption Measurement* available on the Freescale Extranet)
- The PU domain is automatically restored when the system exits from these two modes
- Other domains can be power gated depending on the application use case



# Clock Gating & Peripheral Power (Included in BSP Version GA1209)

Management of peripheral clocks is critical in the reduction of dynamic power for the peripheral domain. The dynamic power consumed by a peripheral module is roughly proportional the frequency of operation. In addition, significant power is consumed by the clock tree itself. A variety of clock management strategies for peripherals including the following:

- Manual clock gating by software via clock gating registers and automatic clock gating (hardware triggered) when the system enters low-power operating modes (WAIT, STOP)
- Auto-slow logic provided by software that can reduce the speed of internal buses such as AHB or AXI during low utilization periods.
- If aggressive clock gating is utilized (run-fast-and-stop), then DFS offers little benefit and could actually increase power due to longer bus duty cycle.

## Peripheral Power

Feature	Linux BSP Mapping
Peripheral Clock Management	Device Driver Clock Framework
PLL Management (enable/disable)	Clock Framework
Peripheral Power Gating	Device Driver Regulator API
Peripheral/Bus DVFS	Clock Framework
I/O Power Management	Device Driver
Voltage Regulator Control	Regulator API



# PHY and IO Power Control

## (Included in BSP Version GA1209)

### PHY

- PHY's can consume considerable power if the circuits are left enabled
- The recommendation is to place all unused PHY's to the lowest power state such as SATA, HDMI and PCIe

### IO Power

- The IOMUX pads should be set to lowest power setting when system is in suspend mode
- All unnecessary PU/PD resistors should be disabled
- Set DDR type IO pads to CMOS mode if possible, specifically for the RGMII segment
- Suspend code is run in IRAM allowing for lower leakage on DDR I/O pads by lowering the drive strengths

*Note : In the current BSP release the DDR IO is set to CMOS mode only in DSM mode*

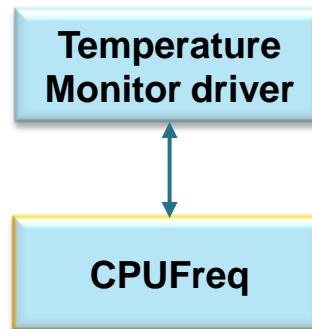


# Thermal Monitor & Protection

(Included in BSP Version GA1209 )

## Overview

- The temperature sensor module (TEMPMON) implements a temperature sensor/conversion function based on a temperature-dependent voltage to time conversion. A self-repeating mode can also be programmed which executes a temperature sensing operation based on a programmed delay
- The module features an alarm function that can raise an interrupt signal if the temperature is above a specified threshold. The current BSP release implements the interrupt signal to notify a system reboot for critical temperature
- CPUFreq works with the temperature monitor driver to ensure that the frequency of the core is lowered when the die temperature is above the specified limit. The current BSP release supports CPUFreq





# Thermal Monitor & Protection

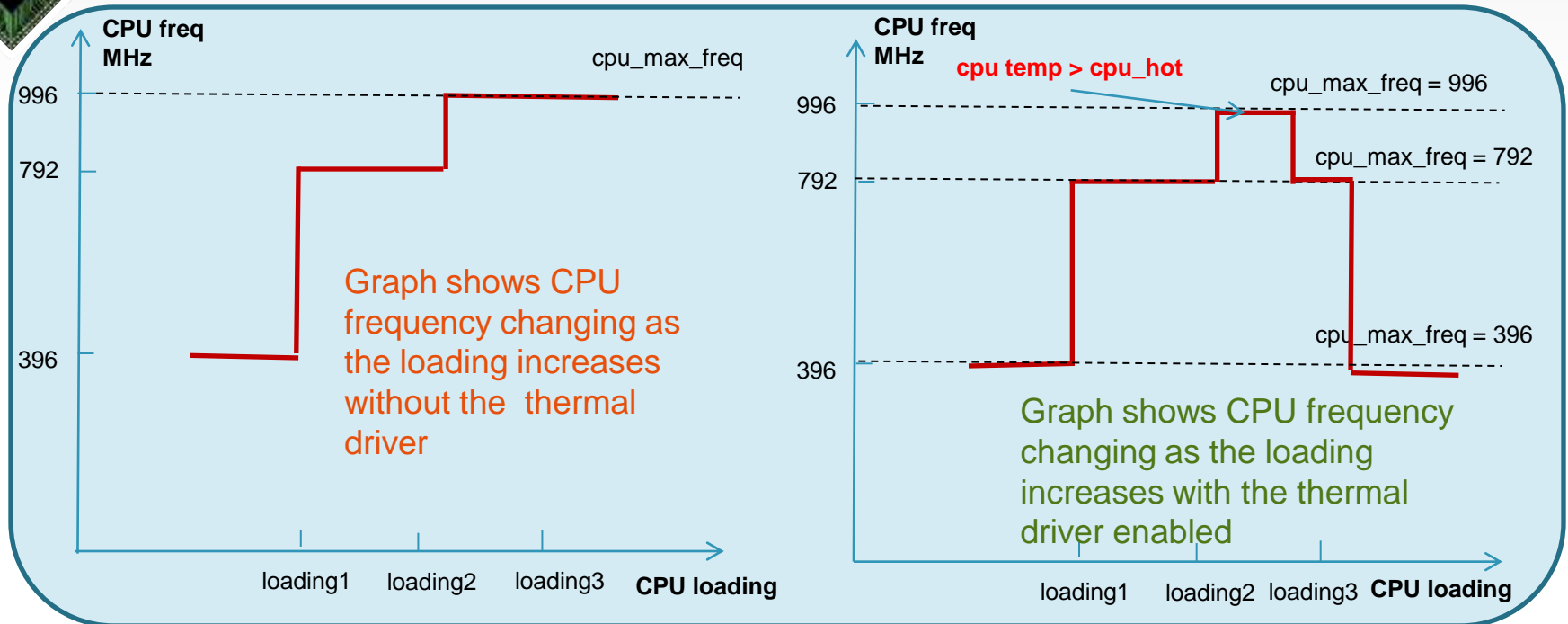
## (Included in BSP Version GA1209 )

### Software Thermal Driver

- Software can use this module to monitor the on-die temperature and take appropriate actions such as throttling back the core frequency or off lining a core when a temperature interrupt is set. The thermal driver requires calibrated parts and reads the calibration data from the fuses.
- The thermal driver implements three threshold points for temperature – critical, hot and active
  - **Critical** : when the measured on die temperature exceeds the critical threshold → reboot the system (protection mechanism to prevent damage). For the Linux BSP GA1209 Release this threshold is programmed to 100 ° C. The thermal driver checks the temperature, and only permits the system to boot up if the temperature is below 80 ° C.
  - **Hot** : when the on die temperature exceeds the hot threshold → reduce the frequency. If the temperature keeps increasing, continue to reduce the frequency using *CPU Freq*. For the Linux BSP GA1209 Release this threshold is programmed to 90 ° C.
  - **Active**: when the on die temperature drops below the active threshold → restore the previous *CPU Freq* driver determined maximum ARM core frequency. For the Linux BSP GA1209 Release this threshold is programmed to 80°C.
- The number of thresholds and respective actions for each, is completely defined in software and can hence be easily modified to cater to the customer specific requirements
- The thermal driver works with *CPU Freq mechanism*. In future BSP releases *CPU hotplug* will also be supported as a cooling device



# DFS Based on CPU Temperature



- As an example for a given CPU loading the *CPU freq* set point is 996MHz and the temperature exceeds the *cpu\_hot* threshold. The CPU thermal driver will adjust the *CPU Freq* governor's *cpu\_max\_freq* to the next lower set point (792MHz). As a result, the CPU frequency is automatically lowered below the *cpu\_max\_freq*
- If the CPU temperature keeps increasing, the thermal driver will again automatically lower the *cpu\_max\_freq* to the next set point (396MHz)
- **The number of thresholds and respective actions for each, is completely defined in software**





# GPU Thermal Management

## Memory or Processing Bounded

- For high performance multimedia use cases such as 3D playback, thermal and power management of the GPU3D core become essential
- Such use cases not only utilize the GPU but are also very DDR memory intensive hence increasing the total system power (DDR + IO)
- It is important to determine, if the system is “memory” bounded or “processing” bounded in target use cases that utilize multiple high performance IP . This is also required for different stages of execution within the use case.
- This determination assists in identifying where the power and heat is being generated hence allows users to throttle the correct master
- In theory, run fast and idle is the best strategy as graphics workloads can be variably sensitive to render latency
- The DVFS strategy for CPU and GPU/VPU/IPU should be “run fast” if “processing” bounded case and frequency downscaling for processing modules in “memory” bounded cases



# GPU Thermal Management

The GPU software driver enables all the power management techniques/features implemented in GPU3D design and the driver does reasonable management of these features

## Internal Clock Gating

- GPU3D facilitates efficient power/clock management policy internally:
  - Fine granular clock gating system that efficiently gate clocks for many modules that temporarily are not active (This feature is enabled by default in the software driver that is part of the current BSP release)
  - It has monitors and software may control internal clock rate modulation

## GPU Frequency Scaling

- For further temperature reduction users can control the GPU performance and in particular the frequency at which the GPU and its sub components run
- The thermal driver can inform the GPU to do perform frequency scaling when the device temperature reaches a certain threshold
- GPU can be programmed to scale all of its clocks such as the AXI, shader and core clock. Depending on the use case the impact of scaling various internal GPU clocks varies, since not all use cases will require all sub components of the GPU. A general understanding of the profile of the power intensive use case assists in frequency scaling the correct sub component
- This temperature aware GPU frequency scaling feature will be incorporated in the post GA BSP release



# LDO Bypass Mode

## Full Digital Bypass Mode

- The i.MX6 series power management system was built under assumption that in typical applications the single (and simple) shared power supply will be used for ARM core domain and SoC domain
- The combined load gains some efficiency, especially in low power modes and can save BOM costs significantly
- In high power mode (highest DVS set-point) the internal regulators (LDOs) are bypassed and have a very small residual resistance ( like regular power gating FETs )
- Thus, using LDO bypass, customers in certain applications may implement a regular DVS based system using a software controllable external PMIC
- While i.MX6 is in low power mode the external PMIC could be switched from normal (PWM) regulation to some of its power saving modes and reduce the voltage drop over internal LDOs
- i.MX6 has dedicated signal to control external DCDC/PMIC switching between normal operations (PWM regulation) and low power modes
- Potential power savings in LDO Bypass mode which will translate directly to thermal savings
- The BSP already supports full bypass for customers that have a programmable PMIC such as PF0100



# Content

- Overview
- Thermal Management Concepts
- Thermal Attributes
- Thermal Simulations
- Software Thermal Management Techniques
- **Recommendations /Conclusion**
- Appendix/References





# Recommendations /Conclusion

## Simulation Results

- Freescale recommends customers to perform thermal simulations on their final form factor device to determine the maximum thermal design power
- When the measured system power for the worst case use cases exceeds this maximum processor power to maintain 85 °C within the enclosure and less than 105 °C junction temperature, thermal management techniques need to be applied
  - Simulation results with a tablet mechanical model using a Freescale SDP PCB board and components with 5W and 2W use cases at ambient temperature of 25 °C shows that the device temperature reaches to 100 °C and 80 °C respectively.
  - LCD screen temperatures were ~ 80 °C and 70 °C for 5W and 2W use cases respectively (Additional heat generating components such as DDR3, LCD(3W) included)



# Recommendations /Conclusion

## Graphite Heat Spreaders

- Various passive thermal management techniques were presented. The most effective from a performance aspect is the graphite heat spreader
- Simulation results show that increasing the heat spreader coverage and thickness increases the thermal design power and allows running higher power consuming applications within the same thermal envelope
- Simulation results showed that with the heat spreader the non lidded package heat dissipation was similar to a lidded package if the heat spreader was applied properly
- There was minimal impact on results due to the change from copper to graphite heat spreader as the main contributor to the temperature decrease was the spreader thickness and dimensions
- The graphite spreader reduced the overall temperature gradient within the device and the enclosure touch temperature
- Increasing the thermal conductivity of the thermal gap filler and interface material marginally improved the system heat dissipation
- Simulations have shown that for 5.6 W and above, incorporation of a spreader alone will not suffice, and additional thermal management techniques will be required to hold the junction temperatures within specification



# Recommendations /Conclusion

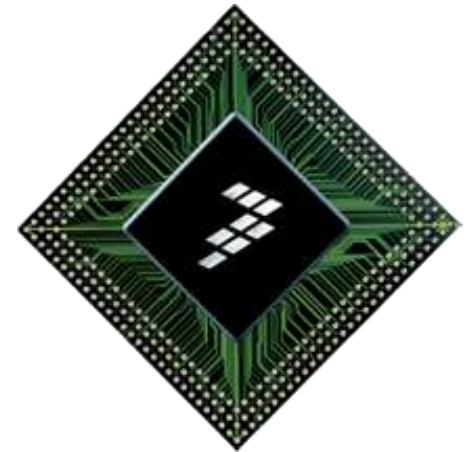
## Software Thermal Management

- The i.MX 6Dual/6Quad SoC incorporates several low-power design techniques and leveraging features and power saving strategies implemented at the device and micro architectural level can have a significant impact on the thermal demand. Heat in an embedded system is a by product of power and the best way to generate less heat is to consume less power.
- Software can take advantage of various hardware features that allow power optimization thereby managing heat dynamically and reducing the need for heat spreaders, heat sinks and metal enclosures
- Various software thermal management techniques were presented that enable customers to remain within the defined thermal enveloped
- A summary of the power management framework within operating systems such as Linux was presented in the context of thermal management. These features such as Temperature Aware DVFS allow throttling of the CPU frequency to reduce the temperature when above the software defined temperature thresholds
- Significant power and thermal savings have been seen with DDR Controller and memory optimizations such as On Die Termination
- Software features that have been made available in the GA 1209 Linux BSP release have been highlighted along with additional features planned for future BSP releases



# Content

- Overview
  - Thermal Management Concepts
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  - Recommendations /Conclusion
- **Appendix/References**







# Appendix A - DDR Interface Power Variables <sup>1</sup>

Issue Affecting Power	Impact
Channel Width	More data bits = more active power
Number of Ranks	More ranks = more ODT termination during Writes and more capacitance load on Address & Command channel
Channel Data Rate	Higher data rate = more power consumption
Ratio of Reads to Writes to Idle cycles on the data bus	Reads use ODT in the PHY and consume power in the input buffers. Writes consume power in the output drivers
Activity ratio of the Address/Command bus	The more switching you have, the more power you consume in external capacitance
Data Switching activity	The more switching you have, the more power you consume in external capacitance
Drive strength & ODT values in the DRAM	Smaller ODT values = higher system power
Drive strength & ODT values in the PHY	Lower impedance drive = higher system power
Termination resistor value for Address/Command bus	Smaller termination values = higher system power
Process Technology	Core power (VDD) varies with feature size. Higher VDD = higher power
PVT	Traditional process, voltage, temperature effects
Pin Loading	Traditional $CV^2F$ power



# Appendix B i.MX 6Dual/6Quad SoC Power Management Features

Feature	Active SoC Power	Standby SoC Power	System Power
LP flavor of 40nm process		✓	
Minimized number of LVT transistors		✓	
<b>Temperature monitoring and active frequency throttling</b>	✓		
<b>ARM DVFS</b>	✓		
ARM SRPG (software)		✓	
ARM Power Gating (Internal switches)		✓	
<b>VPU &amp; GPU3D Power Gating</b>		✓	
Well biasing		✓	
<b>Clock gating (automatic dynamic and forced)</b>	✓		
Integrated PMU (IR drop, efficiency, accuracy)	✓	✓	
<b>C4 package (IR drop, thermal)</b>	✓	✓	
<b>Independent Power gating of IO supplies</b>			✓
<b>Architecture: L2 cache, Video/Audio/Graphics acceleration</b>	✓		
<b>Architecture: USB, PCIe, SATA, HDMI, LVDS integration</b>			✓
<b>Low power DDR: LPDDR2, LV-DDR3</b>			✓



# Appendix C

## Thermal Measurement Glossary

- For standardized thermal performance values, the thermal performance is determined per the JEDEC standards.
- The thermal performance of a package is typically determined on both a single signal layer test board (1s) and on a multi-layer test board (2s2p)
- A single number is generally used to quantify the temperature rise of the circuitry with respect to a specified external location. The thermal resistance value, Theta-JX, where “X” is the external location, is calculated as

$$\text{Theta-JX} = R_{\theta JX} = \frac{T_J - T_X}{\text{Power}} \quad \text{Equation 1}$$

- The temperature difference between the hottest spot on the circuitry (junction) and location “X” is divided by the power dissipation in Equation 1
- Equation 1 also indicates that Theta-JX ( $\theta_{jx}$ ) is used interchangeably with the notation  $R_{\theta JX}$ . The latter is the official JEDEC notation.



# Appendix C

## Thermal Measurement Glossary

### Theta-JA ( $R_{\theta JA}$ )

- Junction to ambient thermal resistance in moving air, Theta-JA ( $R_{\theta JA}$ ) is determined according to EIA/JESD51-6
- Theta-JA is also used to represent the junction-to-ambient thermal resistance obtained on a 2s2p test board in natural convection
- This thermal resistance is recommended in applications where the device is dissipating most of the power, and the device is mounted on a multi-layer board
- If airflow is present, the Theta-JA values can be used as a first estimate to determine if the package will function without a heat sink

### Theta-JC ( $R_{\theta JC}$ )

- Junction-to-case thermal resistance, Theta-JC ( $R_{\theta JC}$ ) is determined using the basic cold plate guidelines described by MIL-STD 883D, Method 1012.15 as the reference specification
- Normally Theta-JC is measured with a thin layer of thermal grease
- Theta-JC is interpreted to be the resistance between the junction and topside of the package when all the heat leaves the top portion of the exposed die
- Theta-JC is used during heat sink selection to meet a specific thermal requirement



# Appendix C

## Thermal Measurement Glossary

### Theta-JB ( $R_{\theta JB}$ )

- Junction-to-board thermal resistance, Theta-JB ( $R_{\theta JB}$ ) is measured or simulated according to JEDEC /JESD51-8
- This parameter shows the thermal resistance between the junction and the board at the perimeter of the package.
- The resulting thermal resistance is recommended in applications where there is a specified maximum board temperature in a natural convection environment or in an enclosed environment.
- Customers can also use this value in system level thermal simulations as part of a two-resistor representation, in conjunction with Theta-JC ( $R_{\theta JC}$ )



# Appendix C

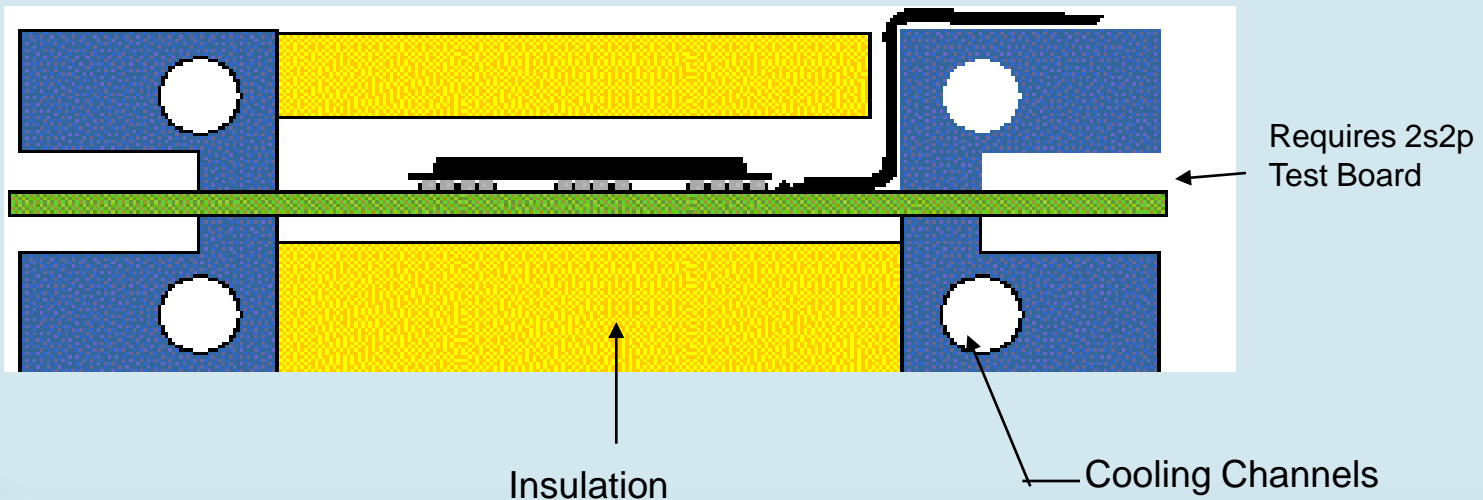
## Thermal Measurement Glossary

### Measuring Junction to Board Thermal Resistance

- For surface mount devices, most of the heat is dissipated to the board and then to the rest of the environment.
- Hence, the thermal resistance to the board is the most important thermal path.
- It is determined per the JEDEC specification JESD51-8.

$$R_{\theta_{JB}} \text{ or } \theta_{JB} = (T_J - T_B)/P$$

Board temperature measured with thermocouple soldered to trace at center of package



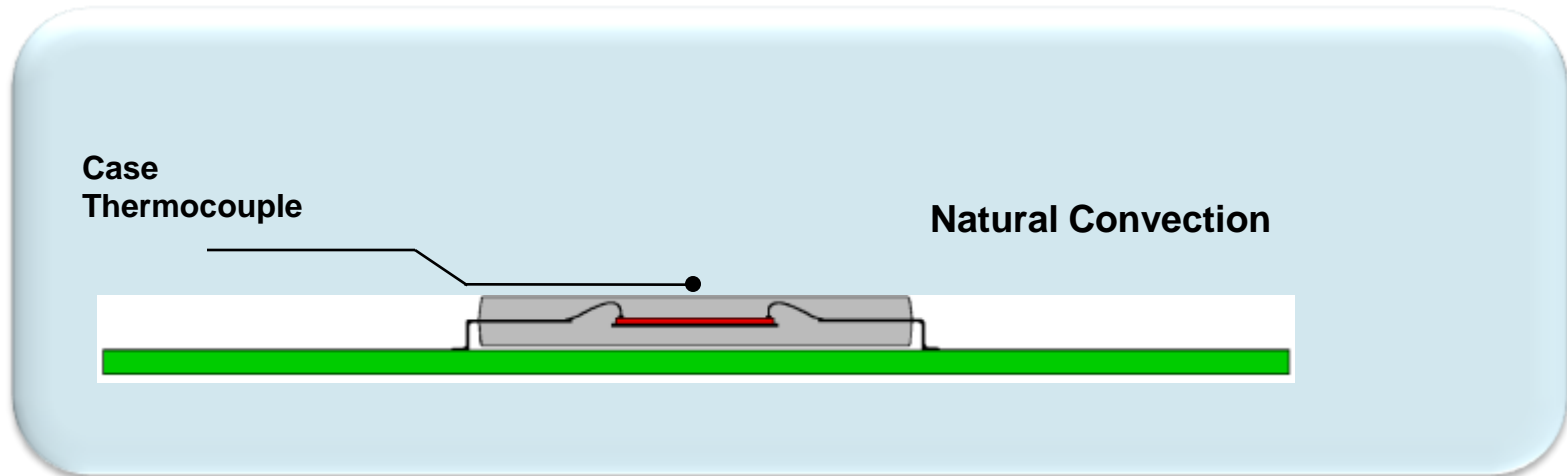


# Appendix C

## Thermal Measurement Glossary

### Determining the Junction Temperature

- Customers need to verify junction temperature for components in their application
- The Thermal Characterization Parameter ( $\Psi_{JT}$  or Psi-JT) meets that need
- It varies slightly with air flow however normally report natural convection values



- Thermocouple should be made with 40 gauge wire with both wire and bead attached to the top center of the package with thermally conductive epoxy. Wire routed next to package body.
- Test method defined in JESD51-2.



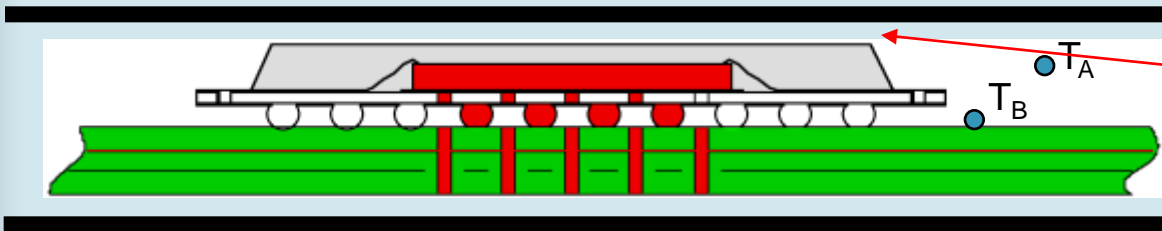
# Appendix C

## Thermal Measurement Glossary

Sealed Box, small vertical spacing,

### Thermal Models for Small Enclosures

**Specify:** Max Board Temperature ( $T_B$ ) and Maximum Case Temperature ( $T_C$ )



If vertical spacing small, then no convection air flow and  $T_B$  is less than few C hotter than  $T_A$ .

- The thermal performance of the component is determined by the board temperature
- The component will have much better thermal performance relative to nearby ambient temperatures than would be predicted by Theta-JA
- The nearby ambient temperature is closer to the board temperature for small enclosures.
- The board temperature also represents the temperature of the largest heat sink available to the part





## Standard Set of Thermal Resistances

Rating	Medium	Symbol	Unit	Notes
Junction to Ambient Natural Convection	Single layer board (1s)	$R_{\theta JA}$	$^{\circ}\text{C/W}$	1,2
Junction to Ambient Natural Convection	Four layer board (2s2p)	$R_{\theta JA}$	$^{\circ}\text{C/W}$	1,2
Junction to Ambient (@200 ft/min)	Single layer board (1s)	$R_{\theta JA}$	$^{\circ}\text{C/W}$	1,3
Junction to Ambient (@200 ft/min)	Four layer board (2s2p)	$R_{\theta JA}$	$^{\circ}\text{C/W}$	1,3
Junction to Board		$R_{\theta JB}$	$^{\circ}\text{C/W}$	4
Junction to Case		$R_{\theta JC}$	$^{\circ}\text{C/W}$	5
Junction to Package Top	Natural Convection	$\theta_{JT}$	$^{\circ}\text{C/W}$	6

1. Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per JEDEC JESD51-2 with the single layer board horizontal. Single layer board per JEDEC specifications such as JESD51-3, JESD51-5, JESD51-9, and others.
3. Junction to moving air thermal resistance per JEDEC JESD51-6 with the board horizontal. Board per JEDEC specifications.
4. Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Indicates the average thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature. *For exposed pad packages where the pad would be expected to be soldered, junction to case thermal resistance is a simulated value from the junction to the exposed pad without contact resistance. For exposed die flip chip packages, a theoretical less than 0.1 C/W is used.*
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.



# Appendix D

## Heat Sink Effects on Thermal Resistance

Heat sinks increase the rate of power dissipation through the top of the exposed die and also decrease the resistance by increasing the surface area.

Example calculation of Tcase and Max power based on previous thermal resistance values with a heat sink

- $P_{DMax} = T_{jMax} - T_A / \theta_{JA}$
- Ambient = 25 deg C
- $T_{jMax} = 105 \text{ deg C}$
- $T_A = 25 \text{ deg C}$

$$P_{DMax} = (105 - 25) / 22 = 3.6W \text{ (without heatsink)}$$

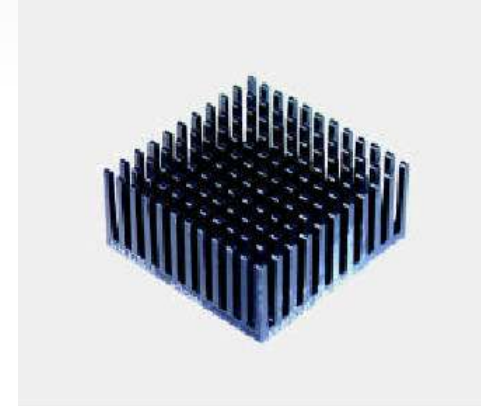
Typical Power	Rating	Board	$R_{\theta JA}$ Value	Value with Heat sink
4 W	Junction to Ambient (Natural Convection)	2s2P Test board	22 C/W	7 C/W



# Appendix D

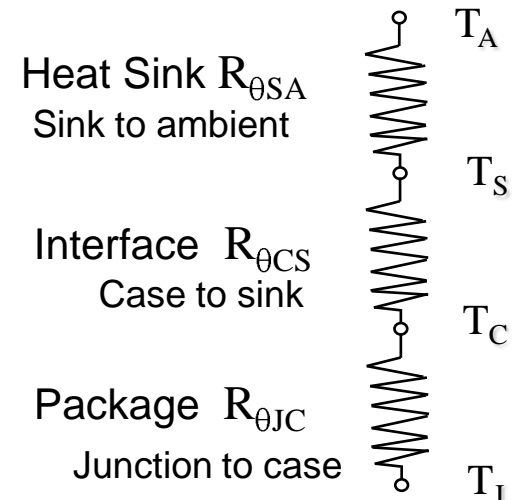
## Heat Sink Selection

- Theta-JC is used during heat sink selection to meet a specific thermal requirement
- Theta-JC is interpreted to be the resistance between the junction and topside of the package when all the heat leaves the top portion of the exposed die
- The addition of a heat spreader will improve the thermal performance of the FC-PBGA package and may permit operation without a heat sink
- Specific heat sinks are not provided because of the range of applications and environments that customers use
- Reference heat sinks may be provided to help customers estimate the heat sink requirements



$$T_J = T_A + (R_{\theta JC} + R_{\theta CS} + R_{\theta SA}) * P$$

- Simple view of Heat Sinks assuming all the heat flows to the heat sink
- Customer models must consider heat flow path through the heat sink and the heat flow to the printed circuit board





# Appendix D: Heat Sink Effects on Thermal Resistance

Table: Thermal Resistance with Heat Sink in Open Flow, No Lid

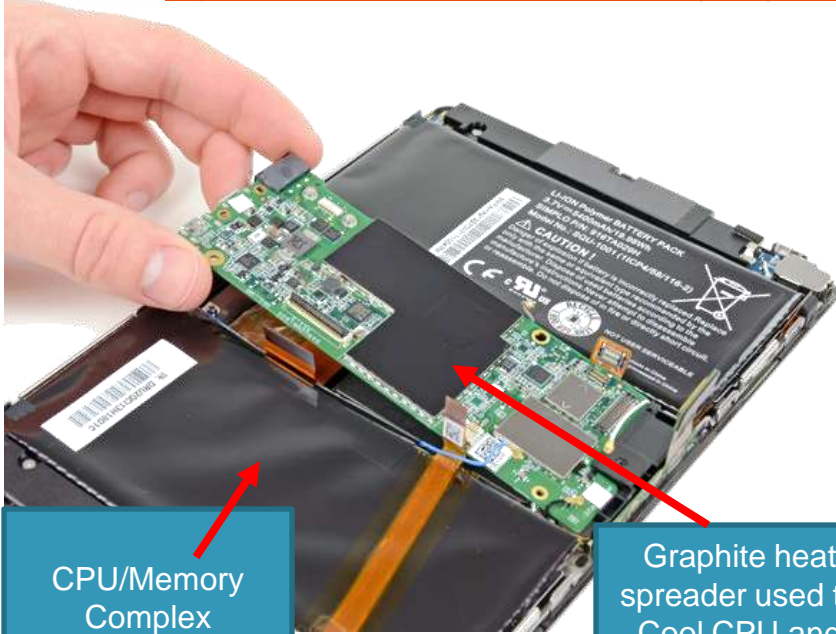
Heat Sink with Thermal Grease	Air Flow	Thermal Resistance (°C/W)	Thermal Resistance (°C/W), better HS TIM
Wakefield 53 x 53 x 25 mm Pin Fin	Natural Convection	6.9	6.4
	0.5 m/s	4.3	3.7
	1 m/s	3.3	2.7
	2 m/s	2.8	2.2
	4 m/s	2.5	1.9
Aavid 35x31x23 mm Pin Fin	Natural Convection	9.2	8.7
	0.5 m/s	5.5	5.0
	1 m/s	4.6	4.1
	2 m/s	4.0	3.4
	4 m/s	3.5	3.0
Aavid 30x30x9.4 mm Pin Fin	Natural Convection	12.9	12.6
	0.5 m/s	8.7	8.4
	1 m/s	6.9	6.5
	2 m/s	5.4	4.9
	4 m/s	4.5	4.0
Aavid 43x41x16.5 mm Pin Fin	Natural Convection	9.3	8.9
	0.5 m/s	5.9	5.4
	1 m/s	4.5	4.0
	2 m/s	3.6	3.0
	4 m/s	3.0	2.4

- Simulations with heat sinks were done with the package mounted on the 2s2p thermal test board.
- The standard thermal interface material was a typical thermal grease, thermal resistance 67 C-mm<sup>2</sup>/W
- The better thermal interface material assumed a Shin-Etsu x23-7772-4 thermal resistance of 25 C-mm<sup>2</sup>/W

# Appendix E

## Thermal Heat Spreader Example

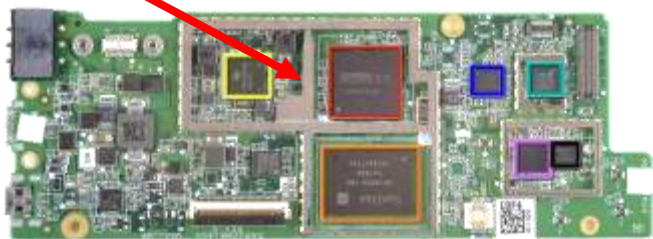
- Teardown Photos: RIM Playback
- Source: <http://www.ifixit.com/Teardown/BlackBerry-PlayBook-Teardown/5265/1#.T8kAB1KRMgc>



CPU/Memory Complex

Graphite heat spreader used to Cool CPU and Memory

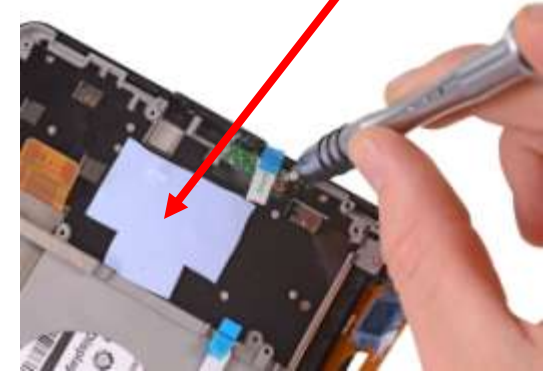
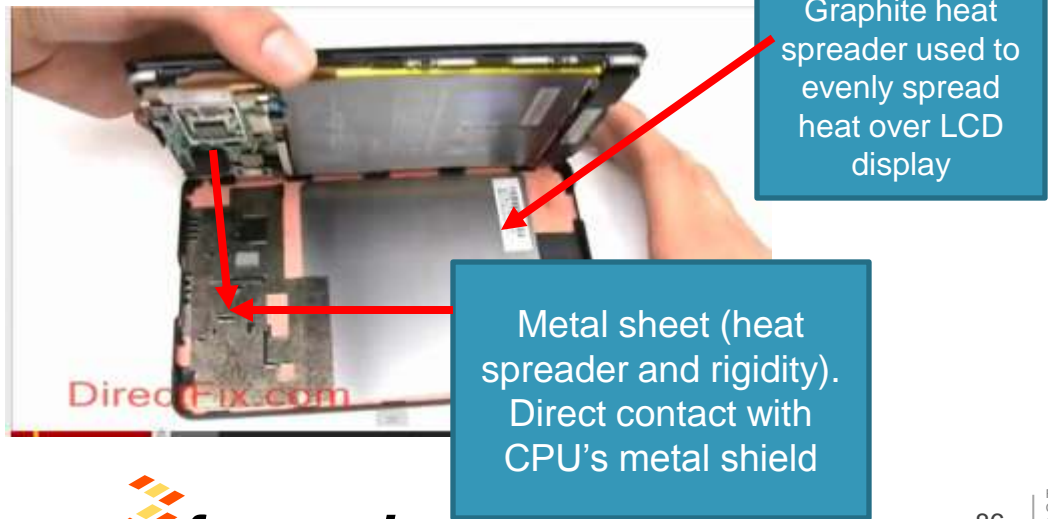
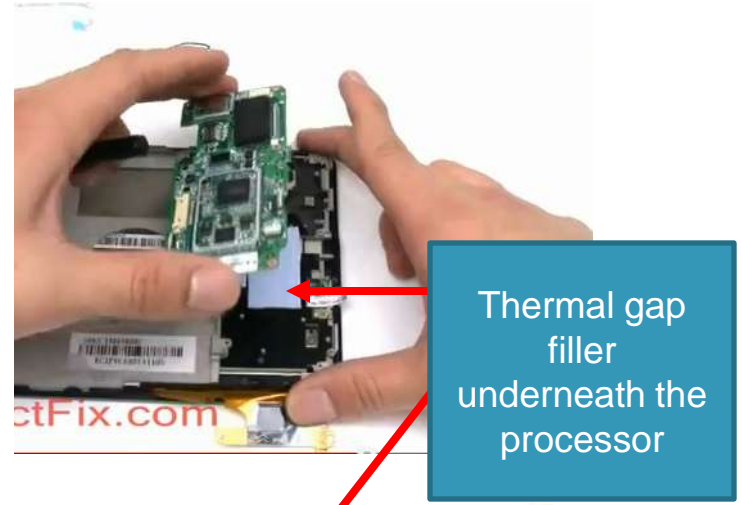
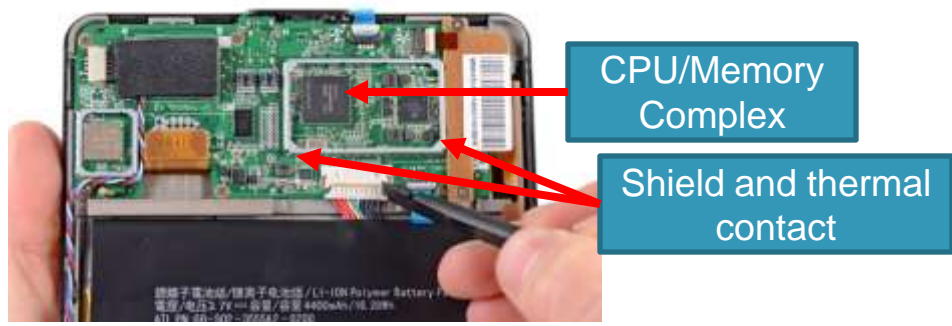
Graphite heat spreader used to Shield heat from reaching the back cover



Graphite Heat spreader Easily cut into any dimension to spread heat into other components

# Appendix E Thermal Heat Spreader Example

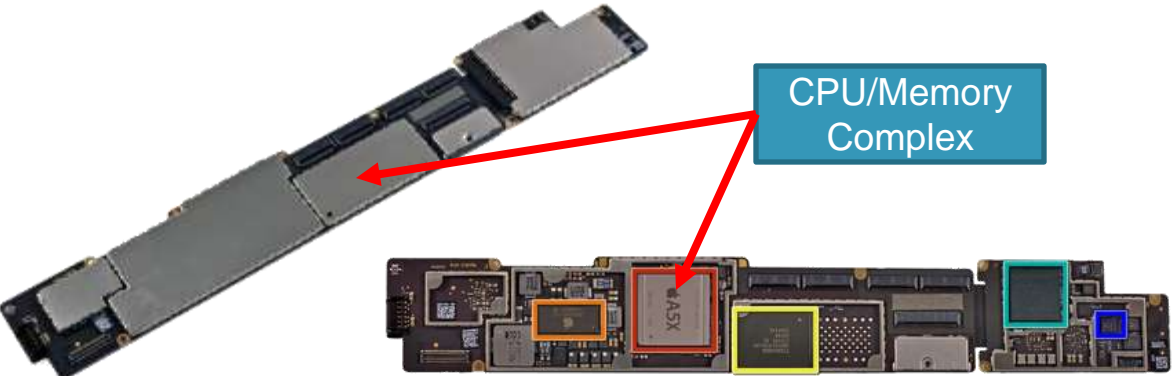
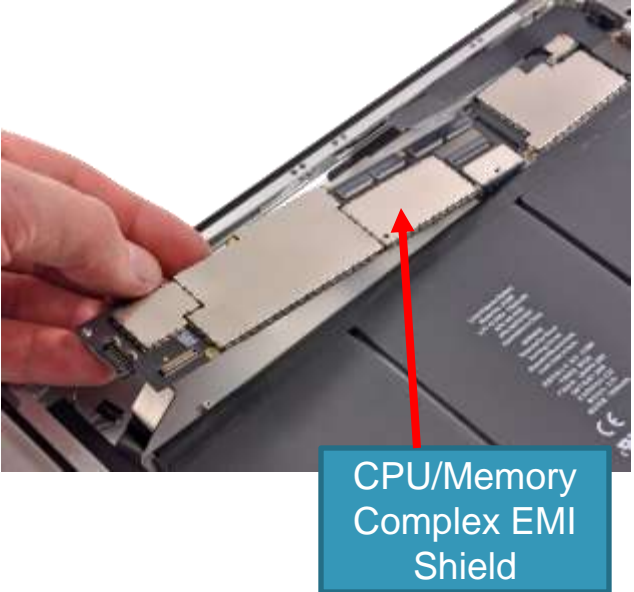
- Teardown Photos: Kindle Fire
- Source: <http://www.ifixit.com/Teardown/Kindle-Fire-Teardown/7099/1#.T8kCmlKRMgf>
- Source: <http://www.youtube.com/watch?v=MGLn1TVAITQ>



# Appendix E

## Thermal Heat Spreader Example

- Teardown Photos: Apple iPad3
- Source: <http://www.ifixit.com/Teardown/iPad-3-4G-Teardown/8277/3>



EMI shield is in direct contact with back of device. Thus acts as EMI as well as thermal spreader



## Thermal Management Technique : Case Study <sup>6</sup>

Two aluminum heat spreaders, one coupled to a lower case made of die cast magnesium alloy, the other to an upper case of ABS plastic, were used to cool a processor by natural convection only. Thermally conductive silicon gap pads were used to conduct heat from the microprocessor and PCB to the rigid aluminum heat spreaders. One disadvantage of this design was that the case touch temperature immediately below the heat source was high.

The following modifications improved the systems thermal management:

- Replacement of the rigid aluminum spreaders with flexible graphite heat spreaders
- Thermally insulating elastomeric materials were placed between the graphite and the case and were used to press the graphite against the heat source.
- The anisotropy of the graphite, combined with the insulation of the elastomer, eliminated the hot spot on the case beneath the processor heat source
- The spreader was designed to lie on top of the components and held in place by the contact pressure generated by the case
- The temperature gradient in the hardware components was significantly modified by the spreaders. The graphite spreaders transferred heat from the hottest component into the cooler surrounding components.
- Increasing either spreader thickness or in-plane thermal conductivity further improved the heat flow and reduced the overall temperature gradient in the components





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